

MX25L3255E HIGH PERFORMANCE SERIAL FLASH SPECIFICATION



MX25L3255E

Contents

2. GENERAL DESCRIPTION 6 Table 1. Read Performance 6 9. PIN CONFIGURATION 7 4. PIN DESCRIPTION 7 5. BLOCK DIAGRAM. 8 6. DATA PROTECTION 7 7. Table 2. Protected Area Sizes 10 Table 3. 4K-bit Secured OTP Definition 11 7. MEMORY ORGANIZATION 12 Table 4. Memory Organization 12 8. DEVICE OPERATION 13 9. HOLD FEATURE 14 10. COMMAND DESCRIPTION 13 9. HOLD FEATURE 14 10. COMMAND DESCRIPTION 15 Table 5. Command Sets 15 10-1. Write Enable (WREN) 18 10-2. Write Disable (WREN) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (WRSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes at Higher Speed (FAST_READ) 27 10-7. Read Data Bytes at Higher Speed (FAST_READ) 28 10-8. Dual Read Mode (QREAD) 30 10-10. Quad Read Mode (QREAD)	Table 1. Read Performance 6 3. PIN CONFIGURATION 7 4. PIN DESCRIPTION 7 5. BLOCK DIAGRAM. 8 6. DATA PROTECTION 9 Table 2. Protected Area Sizes 10 Table 3. 4K-bit Secured OTP Definition 11 7. MEMORY ORGANIZATION 12 Table 4. Memory Organization 12 8. DEVICE OPERATION 13 9. HOLD FEATURE 14 10. COMMAND DESCRIPTION 15 Table 5. Command Sets 15 10-1. Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (WRSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes at Higher Speed (FAST_READ) 28 10-8. Dual Read Mode (DREAD) 28 10-9. 2 x I/O Read Mode (READ) 30 10-11. 4 x I/O Read Mode (READ) 31 10-12. Performance Enhance Mode 33 10-13. Load Read Mode (READ) </th <th>1. FEATU</th> <th>RES</th> <th>4</th>	1. FEATU	RES	4
3. PIN CONFIGURATION 7 4. PIN DESCRIPTION 7 5. BLOCK DIAGRAM 8 6. DATA PROTECTION 9 Table 2. Protected Area Sizes 10 Table 2. Protected Area Sizes 10 Table 3. 4K-bit Secured OTP Definition 11 7. MEMORY ORGANIZATION 12 Table 4. Memory Organization 12 8. DEVICE OPERATION 13 9. HOLD FEATURE 14 10. COMMAND DESCRIPTION 15 Table 5. Command Sets 15 10-1. Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (RDSR) 21 10-5. Write Status Register (RDSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes at Higher Speed (FAST_READ) 27 10-7. Read Data Bytes at Higher Speed (FAST_READ) 29 10-8. Dual Read Mode (QREAD) 30 10-10. Quad Read Mode (QREAD) 31 10-12. Performance Enhance Mode 33 10-	3. PIN CONFIGURATION 7 4. PIN DESCRIPTION 7 5. BLOCK DIAGRAM 8 6. DATA PROTECTION 7 5. BLOCK DIAGRAM 8 6. DATA PROTECTION 9 Table 2. Frotected Area Sizes 10 Table 3. 4K-bit Secured OTP Definition 11 7. MEMORY ORGANIZATION 12 Table 4. Memory Organization 12 5. DEVICE OPERATION 13 9. HOLD FEATURE 14 10. COMMAND DESCRIPTION 15 Table 5. Command Sets 15 10-1. Write Enable (WREN) 18 10-2. Write Disable (WREN) 18 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Sitaus Register (WRSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes at Higher Speed (FAST_READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (QREAD) 29 10-9. 2 x I/O Read Mode (QREAD) 30 10-10. Quad Read Mode (QREAD) 31 10-11. 4 x I/O Read Mode (QREAD) 32 </td <td>2. GENER</td> <td>RAL DESCRIPTION</td> <td>6</td>	2. GENER	RAL DESCRIPTION	6
4. PIN DESCRIPTION 7 5. BLOCK DIAGRAM 8 6. DATA PROTECTION 9 Table 2. Protected Area Sizes 10 Table 3. 4K-bit Secured OTP Definition 11 7. MEMORY ORGANIZATION 12 Table 4. Memory Organization 12 Stable 5. Command Sets 13 9. HOLD FEATURE 14 10. COMMAND DESCRIPTION 15 Table 5. Command Sets 15 10-1. Write Disable (WREN) 18 10-2. Write Disable (WREN) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (WRSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes (READ) 29 10-8. Dual Read Mode (QREAD) 30 10-10. Quad Read Mode (QREAD) 32 10-11. 4x I/O Read Mode (QREAD) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode 33 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) <t< td=""><td>4. PIN DESCRIPTION 7 5. BLOCK DIAGRAM. 8 6. DATA PROTECTION. 9 Table 2. Protected Area Sizes 10 Table 3. 4K-bit Secured OTP Definition 11 7. MEMORY ORGANIZATION 12 Table 4. Memory Organization 12 8. DEVICE OPERATION 13 9. HOLD FEATURE 14 10. COMMAND DESCRIPTION 15 Table 5. Command Sets 15 10-1. Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (WRSR) 24 10-5. Write Status Register (RDSR) 24 10-5. Read Data Bytes (READ) 27 10-7. Read Data Bytes (READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (QREAD) 31 10-11. 4 x I/O Read Mode (QREAD) 31 10-12. Performance Enhance Mode 33 10-13. Block Erase (BE) 36 10-14. Scotor Erase (SE) 36 10-15. Block Erase (BE) 36 10-16. Block Erase (BE) 36</td><td></td><td>Table 1. Read Performance</td><td>6</td></t<>	4. PIN DESCRIPTION 7 5. BLOCK DIAGRAM. 8 6. DATA PROTECTION. 9 Table 2. Protected Area Sizes 10 Table 3. 4K-bit Secured OTP Definition 11 7. MEMORY ORGANIZATION 12 Table 4. Memory Organization 12 8. DEVICE OPERATION 13 9. HOLD FEATURE 14 10. COMMAND DESCRIPTION 15 Table 5. Command Sets 15 10-1. Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (WRSR) 24 10-5. Write Status Register (RDSR) 24 10-5. Read Data Bytes (READ) 27 10-7. Read Data Bytes (READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (QREAD) 31 10-11. 4 x I/O Read Mode (QREAD) 31 10-12. Performance Enhance Mode 33 10-13. Block Erase (BE) 36 10-14. Scotor Erase (SE) 36 10-15. Block Erase (BE) 36 10-16. Block Erase (BE) 36		Table 1. Read Performance	6
5. BLOCK DIAGRAM	5. BLOCK DIAGRAM	3. PIN CC	ONFIGURATION	7
6. DATA PROTECTION	6. DATA PROTECTION 9 Table 2. Protected Area Sizes 10 Table 3. 4K-bit Secured OTP Definition 11 7. MEMORY ORGANIZATION 12 Table 4. Memory Organization 12 8. DEVICE OPERATION 13 9. HOLD FEATURE 14 10. COMMAND DESCRIPTION 15 Table 5. Command Sets 15 10-1. Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (WRSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes at Higher Speed (FAST_READ) 28 10-8. Dual Read Mode (QREAD) 30 10-10. Quad Read Mode (QREAD) 30 10-11. 4 x I/O Read Mode (READ) 31 10-11. 4 x I/O Read Mode (READ) 32 10-12. Performance Enhance Mode 33 10-13. Preformance Enhance Mode Reset (FFh) 36 10-14. X I/O Read Bytes (KEAD) 37	4. PIN DE	SCRIPTION	7
Table 2. Protected Area Sizes 10 Table 3. 4K-bit Secured OTP Definition 11 7. MEMORY ORGANIZATION 12 Table 4. Memory Organization 12 8. DEVICE OPERATION 13 9. HOLD FEATURE 14 10. COMMAND DESCRIPTION 15 Table 5. Command Sets 15 10-1. Write Disable (WREN) 18 10-2. Write Disable (WREN) 18 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (RDSR) 21 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes (READ) 27 10-7. Read Data Bytes (READ) 29 10-8. Dual Read Mode (QREAD) 29 10-9. 2 x I/O Read Mode (QREAD) 30 10-10. Quad Read Mode (QREAD) 30 10-11. 4 x I/O Read Mode (READ) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 37 <	Table 2. Protected Area Sizes 10 Table 3. 4K-bit Secured OTP Definition 11 7. MEMORY ORGANIZATION 12 Table 4. Memory Organization 12 8. DEVICE OPERATION 13 9. HOLD FEATURE 14 10. COMMAND DESCRIPTION 15 Table 5. Command Sets 15 10-1. Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (WSR) 21 10-5. Write Status Register (WSR) 21 10-5. Write Status Register (WSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes (READ) 29 10-8. Dual Read Mode (QREAD) 29 10-9. 2 x I/O Read Mode (READ) 29 10-10. Quad Read Mode (QREAD) 30 10-11. 4 x I/O Read Mode (READ) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode 33 10-14. Sector Erase (BE) 36 10-15. Block Erase (BE) 36 10-16.	5. BLOCK	(DIAGRAM	8
Table 3. 4K-bit Secured OTP Definition 11 7. MEMORY ORGANIZATION 12 Table 4. Memory Organization 12 B. DEVICE OPERATION 13 9. HOLD FEATURE 14 10. COMMAND DESCRIPTION 15 Table 5. Command Sets 15 10-1. Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (WRSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes (READ) 29 10-9. 2 x I/O Read Mode (DREAD) 30 10-10. Quad Read Mode (QREAD) 30 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 36 10-17. Chip Erase (CE) 38 10-17. Chip Erase (CE) 38 10-17. Chip Erase (CE) 39 10-18. Block Erase (BE) 37 10-19. 4 x I/O Page Pro	Table 3. 4K-bit Secured OTP Definition 11 7. MEMORY ORGANIZATION 12 Table 4. Memory Organization 12 8. DEVICE OPERATION 13 9. HOLD FEATURE 14 10. COMMAND DESCRIPTION 15 Table 5. Command Sets 15 10.1. Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10.3. Read Identification (RDID) 20 10.4. Read Status Register (RDSR) 21 10.5. Write Status Register (WRSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes at Higher Speed (FAST_READ) 27 10-7. Read Data Bytes at Higher Speed (FAST_READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (QREAD) 30 10-10. Quad Read Mode (QREAD) 31 10-11. 4 x I/O Read Mode (READ) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 37 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 37 10-17. Dip Erase (CE) 38 </td <td>6. DATA F</td> <td>PROTECTION</td> <td>9</td>	6. DATA F	PROTECTION	9
Table 3. 4K-bit Secured OTP Definition 11 7. MEMORY ORGANIZATION 12 Table 4. Memory Organization 12 B. DEVICE OPERATION 13 9. HOLD FEATURE 14 10. COMMAND DESCRIPTION 15 Table 5. Command Sets 15 10-1. Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (WRSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes (READ) 29 10-9. 2 x I/O Read Mode (DREAD) 30 10-10. Quad Read Mode (QREAD) 30 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 36 10-17. Chip Erase (CE) 38 10-17. Chip Erase (CE) 38 10-17. Chip Erase (CE) 39 10-18. Block Erase (BE) 37 10-19. 4 x I/O Page Pro	Table 3. 4K-bit Secured OTP Definition 11 7. MEMORY ORGANIZATION 12 Table 4. Memory Organization 12 8. DEVICE OPERATION 13 9. HOLD FEATURE 14 10. COMMAND DESCRIPTION 15 Table 5. Command Sets 15 10.1. Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10.3. Read Identification (RDID) 20 10.4. Read Status Register (RDSR) 21 10.5. Write Status Register (WRSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes at Higher Speed (FAST_READ) 27 10-7. Read Data Bytes at Higher Speed (FAST_READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (QREAD) 30 10-10. Quad Read Mode (QREAD) 31 10-11. 4 x I/O Read Mode (READ) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 37 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 37 10-17. Dip Erase (CE) 38 </td <td>-</td> <td>Table 2. Protected Area Sizes</td> <td></td>	-	Table 2. Protected Area Sizes	
7. MEMORY ORGANIZATION 12 Table 4. Memory Organization 12 8. DEVICE OPERATION 13 9. HOLD FEATURE 14 10. COMMAND DESCRIPTION 15 Table 5. Command Sets 15 10-1. Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (WRSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes (READ) 29 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (QREAD) 30 10-10. Quad Read Mode (QREAD) 31 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (BE) 37 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 37 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Pr	7. MEMORY ORGANIZATION 12 Table 4. Memory Organization 13 8. DEVICE OPERATION 13 9. HOLD FEATURE 14 10. COMMAND DESCRIPTION 15 Table 5. Command Sets 15 10-1 Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (RDSR) 21 10-5. Write Status Register (RDSR) 24 10-6. Read Data Bytes (READ) 26 10-7. Read Data Bytes (READ) 27 10-7. Read Data Bytes (READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (QREAD) 30 10-10. Quad Read Mode (QREAD) 31 10-11. 4 x I/O Read Mode (QREAD) 32 10-12. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 37 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 37 10-17. Chip Erase (CE) 39 10-18. Page Program (APP) 40			
8. DEVICE OPERATION 13 9. HOLD FEATURE. 14 10. COMMAND DESCRIPTION 15 Table 5. Command Sets 15 10-1. Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (WRSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes at Higher Speed (FAST_READ) 29 10-9. 2 x I/O Read Mode (DREAD) 29 10-10. Quad Read Mode (QREAD) 30 10-11. 4 x I/O Read Mode (QREAD) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 37 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (DP) 46	8. DEVICE OPERATION 13 9. HOLD FEATURE 14 10. COMMAND DESCRIPTION 15 Table 5. Command Sets 15 10-1. Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (WRSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes (READ) 28 10-8. Dual Read Mode (DREAD) 28 10-9. 2 x I/O Read Mode (QREAD) 30 10-10. Quad Read Mode (QREAD) 30 10-11. 4 x I/O Read Mode (QREAD) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Frase (SE) 36 10-15. Block Erase (BE32K) 38 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (APP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (RDP), Read Electronic Signature (RES)	7. MEMO		
8. DEVICE OPERATION 13 9. HOLD FEATURE. 14 10. COMMAND DESCRIPTION 15 Table 5. Command Sets 15 10-1. Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (WRSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes at Higher Speed (FAST_READ) 29 10-9. 2 x I/O Read Mode (DREAD) 29 10-10. Quad Read Mode (QREAD) 30 10-11. 4 x I/O Read Mode (QREAD) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 37 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (DP) 46	8. DEVICE OPERATION 13 9. HOLD FEATURE 14 10. COMMAND DESCRIPTION 15 Table 5. Command Sets 15 10-1. Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (WRSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes (READ) 28 10-8. Dual Read Mode (DREAD) 28 10-9. 2 x I/O Read Mode (QREAD) 30 10-10. Quad Read Mode (QREAD) 30 10-11. 4 x I/O Read Mode (QREAD) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Frase (SE) 36 10-15. Block Erase (BE32K) 38 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (APP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (RDP), Read Electronic Signature (RES)		Table 4. Memory Organization	12
10. COMMAND DESCRIPTION 15 Table 5. Command Sets 15 10-1. Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (WRSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes (READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (2READ) 30 10-10. Quad Read Mode (QREAD) 31 10-11. 4 x I/O Read Mode (AREAD) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 37 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Trogram mode (CP mode) 44 10-20. Continuous Program mode (CP mode) 44	10. COMMAND DESCRIPTION	8. DEVIC		
Table 5. Command Sets. 15 10-1. Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (WRSR) 24 Table 6. Protection Modes. 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes (READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (QREAD) 30 10-10. Quad Read Mode (QREAD) 31 10-11. 4 x I/O Read Mode (AREAD) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 37 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (APP) 41 10-20. Continuous Program mode (CP mode) 44	Table 5. Command Sets. 15 10-1. Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (WRSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes (READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (QREAD) 30 10-10. Quad Read Mode (QREAD) 31 10-11. 4 x I/O Read Mode (QREAD) 31 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 37 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-20. Continuous Program mode (CP mode) 41 <td< td=""><td>9. HOLD</td><td>FEATURE</td><td></td></td<>	9. HOLD	FEATURE	
Table 5. Command Sets. 15 10-1. Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (WRSR) 24 Table 6. Protection Modes. 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes (READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (QREAD) 30 10-10. Quad Read Mode (QREAD) 31 10-11. 4 x I/O Read Mode (AREAD) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 37 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (APP) 41 10-20. Continuous Program mode (CP mode) 44	Table 5. Command Sets. 15 10-1. Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (WRSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes (READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (QREAD) 30 10-10. Quad Read Mode (QREAD) 31 10-11. 4 x I/O Read Mode (QREAD) 31 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 37 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-20. Continuous Program mode (CP mode) 41 <td< td=""><td>10. COM</td><td>MAND DESCRIPTION</td><td></td></td<>	10. COM	MAND DESCRIPTION	
10-1. Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (WRSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes at Higher Speed (FAST_READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (2READ) 30 10-10. Quad Read Mode (QREAD) 30 10-11. 4 x I/O Read Mode (2READ) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode 33 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 38 10-17. Chip Erase (CE) 38 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41	10-1. Write Enable (WREN) 18 10-2. Write Disable (WRDI) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (WRSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes at Higher Speed (FAST_READ) 28 10-8. Dual Read Mode (QREAD) 29 10-9. 2 x I/O Read Mode (QREAD) 30 10-10. Quad Read Mode (QREAD) 31 10-11. 4 x I/O Read Mode (AREAD) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 39 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (APP) 40 10-20. Continuous Program mode (CP mode)			
10-2. Write Disable (WRDI)	10-2. Write Disable (WRDI) 19 10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (WRSR) 24 Table 6. Protection Modes. 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes at Higher Speed (FAST_READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (QREAD) 30 10-10. Quad Read Mode (QREAD) 31 10-11. 4 x I/O Read Mode (QREAD) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 37 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 39 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (DP) </td <td>10-1.</td> <td></td> <td></td>	10-1.		
10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (WRSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes at Higher Speed (FAST_READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (QREAD) 30 10-10. Quad Read Mode (QREAD) 30 10-11. 4 x I/O Read Mode (QREAD) 31 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 37 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44	10-3. Read Identification (RDID) 20 10-4. Read Status Register (RDSR) 21 10-5. Write Status Register (WRSR) 24 Table 6. Protection Modes 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes (READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (QREAD) 30 10-10. Quad Read Mode (QREAD) 30 10-11. Quad Read Mode (QREAD) 31 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode 33 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 36 10-16. Block Erase (BE) 37 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (MPP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Reales from Deep Power-down (RDP), Read Electronic Signature (RES) 47 10-23. Read Electronic Manufacturer ID & Device ID (REMS), (REMS2), (REMS4) 49 10-24. ID Read 50 10-25. Enter Secured OTP (ENSO) 50 10-26. Exit Secured OTP (EXSO) 50 10-27. Read Security Register (RDSCUR)			
10-5. Write Status Register (WRSR). 24 Table 6. Protection Modes. 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes at Higher Speed (FAST_READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (2READ) 30 10-10. Quad Read Mode (QREAD) 30 10-11. 4 x I/O Read Mode (4READ) 32 10-12. Performance Enhance Mode 33 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 38 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (DP) 46	10-5. Write Status Register (WRSR). 24 Table 6. Protection Modes. 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes at Higher Speed (FAST_READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (QREAD) 30 10-10. Quad Read Mode (QREAD) 30 10-11. 4 x I/O Read Mode (AREAD) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 37 10-16. Block Erase (CE) 38 10-17. Chip Erase (CE) 39 10-18. Page Program (4PP) 41 10-20. Continuous Program (4PP) 46 10-22. Release from Deep Power-down (RDP), Read Electronic Signature (RES) 47 10-23. Read Electronic Manufacturer ID & Device ID (REMS), (REMS2), (REMS4) 49 10-24. ID Read 50 50	10-3.		
Table 6. Protection Modes. 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes at Higher Speed (FAST_READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (2READ) 30 10-10. Quad Read Mode (QREAD) 30 10-11. 4 x I/O Read Mode (4READ) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 37 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44	Table 6. Protection Modes. 25 10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes at Higher Speed (FAST_READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (QREAD) 30 10-10. Quad Read Mode (QREAD) 30 10-11. Quad Read Mode (QREAD) 31 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode 33 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 37 10-17. Chip Erase (CE) 38 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (DP) 41 10-22. Release from Deep Power-down (RDP), Read Electronic Signature (RES) 47 10-23. Read Electronic Manufacturer ID & Device ID (REMS), (REMS2), (REMS4) 49 10-24. ID Read 50 10-25. Enter Secured OTP (ENSO) 50 10-26. Exit Secured OTP (ENSO) 50 10-27. Read Security Register (RDSCUR) 50	10-4.	Read Status Register (RDSR)	21
10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes at Higher Speed (FAST_READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (2READ) 30 10-10. Quad Read Mode (QREAD) 31 10-11. 4 x I/O Read Mode (4READ) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode 33 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE32K) 38 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44	10-6. Read Data Bytes (READ) 27 10-7. Read Data Bytes at Higher Speed (FAST_READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (2READ) 30 10-10. Quad Read Mode (QREAD) 31 10-11. 4 x I/O Read Mode (4READ) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode 33 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 36 10-16. Block Erase (BE) 37 10-16. Block Erase (BE2XK) 38 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (DP) 46 10-22. Release from Deep Power-down (RDP), Read Electronic Signature (RES) 47 10-23. Read Electronic Manufacturer ID & Device ID (REMS), (REMS2), (REMS4) 49 10-24. ID Read. 50 10-25. Enter Secured OTP (ENSO) 50 10-26. Exit Secured OTP (ENSO) 50 10-27. Read Security Register (RDSCUR) 50	10-5.	Write Status Register (WRSR)	24
10-7. Read Data Bytes at Higher Speed (FAST_READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (2READ) 30 10-10. Quad Read Mode (QREAD) 31 10-11. 4 x I/O Read Mode (4READ) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE32K) 38 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (DP) 46	10-7. Read Data Bytes at Higher Speed (FAST_READ) 28 10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (2READ) 30 10-10. Quad Read Mode (QREAD) 31 10-11. 4 x I/O Read Mode (4READ) 32 10-12. Performance Enhance Mode 33 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-6. Block Erase (BE) 37 10-16. Block Erase (CE) 38 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (DP) 46 10-22. Release from Deep Power-down (RDP), Read Electronic Signature (RES) 47 10-23. Read Electronic Manufacturer ID & Device ID (REMS), (REMS2), (REMS4) 49 10-24. ID Read 50 <td< td=""><td></td><td>Table 6. Protection Modes</td><td>25</td></td<>		Table 6. Protection Modes	25
10-8. Dual Read Mode (DREAD). 29 10-9. 2 x I/O Read Mode (2READ) 30 10-10. Quad Read Mode (QREAD) 31 10-11. 4 x I/O Read Mode (4READ) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 37 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (DP) 46	10-8. Dual Read Mode (DREAD) 29 10-9. 2 x I/O Read Mode (2READ) 30 10-10. Quad Read Mode (QREAD) 31 10-11. 4 x I/O Read Mode (4READ) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 37 10-17. Chip Erase (CE) 38 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (DP) 46 10-22. Release from Deep Power-down (RDP), Read Electronic Signature (RES) 47 10-23. Read Electronic Manufacturer ID & Device ID (REMS), (REMS2), (REMS4) 49 10-24. ID Read 50 10-25. Enter Secured OTP (ENSO) 50 10-26. Exit Secured OTP (EXSO) 50 10-27. Read Security Register (RDSCUR) 51	10-6.	Read Data Bytes (READ)	27
10-9. 2 x I/O Read Mode (2READ) .30 10-10. Quad Read Mode (QREAD) .31 10-11. 4 x I/O Read Mode (4READ) .32 10-12. Performance Enhance Mode .33 10-13. Performance Enhance Mode Reset (FFh) .35 10-14. Sector Erase (SE) .36 10-15. Block Erase (BE) .37 10-16. Block Erase (BE) .38 10-17. Chip Erase (CE) .39 10-18. Page Program (PP) .40 10-19. 4 x I/O Page Program (4PP) .41 10-20. Continuous Program mode (CP mode) .44 10-21. Deep Power-down (DP) .46	10-9. 2 x I/O Read Mode (2READ) 30 10-10. Quad Read Mode (QREAD) 31 10-11. 4 x I/O Read Mode (4READ) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 36 10-16. Block Erase (BE32K) 38 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (DP) 46 10-22. Release from Deep Power-down (RDP), Read Electronic Signature (RES) 47 10-23. Read Electronic Manufacturer ID & Device ID (REMS), (REMS2), (REMS4) 49 10-24. ID Read 50 Table 7. ID Definitions 50 10-25. Enter Secured OTP (ENSO) 50 10-26. Exit Secured OTP (ENSO) 50 10-27. Read Security Register (RDSCUR) 51	10-7.	Read Data Bytes at Higher Speed (FAST_READ)	28
10-10. Quad Read Mode (QREAD) 31 10-11. 4 x I/O Read Mode (4READ) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 38 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (DP) 46	10-10. Quad Read Mode (QREAD) 31 10-11. 4 x I/O Read Mode (4READ) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE) 37 10-17. Chip Erase (CE) 38 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (DP) 46 10-22. Release from Deep Power-down (RDP), Read Electronic Signature (RES) 47 10-23. Read Electronic Manufacturer ID & Device ID (REMS), (REMS2), (REMS4) 49 10-24. ID Read 50 Table 7. ID Definitions 50 10-25. Enter Secured OTP (ENSO) 50 10-26. Exit Secured OTP (ENSO) 50 10-27. Read Security Register (RDSCUR) 51	10-8.	Dual Read Mode (DREAD)	29
10-11. 4 x I/O Read Mode (4READ) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE32K) 38 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (DP) 46	10-11. 4 x I/O Read Mode (4READ) 32 10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE32K) 38 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (DP) 46 10-22. Release from Deep Power-down (RDP), Read Electronic Signature (RES) 47 10-23. Read Electronic Manufacturer ID & Device ID (REMS), (REMS2), (REMS4) 49 10-24. ID Read 50 Table 7. ID Definitions 50 10-25. Enter Secured OTP (ENSO) 50 10-26. Exit Secured OTP (EXSO) 50 10-27. Read Security Register (RDSCUR) 51			
10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE32K) 38 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (DP) 46	10-12. Performance Enhance Mode 33 10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE32K) 38 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (DP) 46 10-22. Release from Deep Power-down (RDP), Read Electronic Signature (RES) 47 10-23. Read Electronic Manufacturer ID & Device ID (REMS), (REMS2), (REMS4) 49 10-24. ID Read 50 Table 7. ID Definitions 50 10-25. Enter Secured OTP (ENSO) 50 10-26. Exit Secured OTP (EXSO) 50 10-27. Read Security Register (RDSCUR) 51			
10-13. Performance Enhance Mode Reset (FFh) 35 10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE32K) 38 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (DP) 46	10-13. Performance Enhance Mode Reset (FFh). 35 10-14. Sector Erase (SE). 36 10-15. Block Erase (BE). 37 10-16. Block Erase (BE32K). 38 10-17. Chip Erase (CE). 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP). 41 10-20. Continuous Program mode (CP mode). 44 10-21. Deep Power-down (DP). 46 10-22. Release from Deep Power-down (RDP), Read Electronic Signature (RES). 47 10-23. Read Electronic Manufacturer ID & Device ID (REMS), (REMS2), (REMS4). 49 10-24. ID Read. 50 Table 7. ID Definitions 50 10-25. Enter Secured OTP (ENSO). 50 10-26. Exit Secured OTP (ENSO). 50 10-27. Read Security Register (RDSCUR). 51			
10-14. Sector Erase (SE)	10-14. Sector Erase (SE) 36 10-15. Block Erase (BE) 37 10-16. Block Erase (BE32K) 38 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (DP) 46 10-22. Release from Deep Power-down (RDP), Read Electronic Signature (RES) 47 10-23. Read Electronic Manufacturer ID & Device ID (REMS), (REMS2), (REMS4) 49 10-24. ID Read 50 Table 7. ID Definitions 50 10-25. Enter Secured OTP (ENSO) 50 10-26. Exit Secured OTP (EXSO) 50 10-27. Read Security Register (RDSCUR) 51			
10-15. Block Erase (BE) 37 10-16. Block Erase (BE32K) 38 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (DP) 46	10-15. Block Erase (BE)			
10-16. Block Erase (BE32K) 38 10-17. Chip Erase (CE) 39 10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (DP) 46	10-16. Block Erase (BE32K)			
10-17. Chip Erase (CE)	10-17. Chip Erase (CE)			
10-18. Page Program (PP) 40 10-19. 4 x I/O Page Program (4PP) 41 10-20. Continuous Program mode (CP mode) 44 10-21. Deep Power-down (DP) 46	10-18. Page Program (PP)			
10-19. 4 x I/O Page Program (4PP) .41 10-20. Continuous Program mode (CP mode) .44 10-21. Deep Power-down (DP) .46	10-19. 4 x I/O Page Program (4PP)4110-20. Continuous Program mode (CP mode)4410-21. Deep Power-down (DP)4610-22. Release from Deep Power-down (RDP), Read Electronic Signature (RES)4710-23. Read Electronic Manufacturer ID & Device ID (REMS), (REMS2), (REMS4)4910-24. ID Read50Table 7. ID Definitions5010-25. Enter Secured OTP (ENSO)5010-26. Exit Secured OTP (EXSO)5010-27. Read Security Register (RDSCUR)51			
10-20. Continuous Program mode (CP mode)	10-20. Continuous Program mode (CP mode). 44 10-21. Deep Power-down (DP). 46 10-22. Release from Deep Power-down (RDP), Read Electronic Signature (RES) 47 10-23. Read Electronic Manufacturer ID & Device ID (REMS), (REMS2), (REMS4) 49 10-24. ID Read. 50 Table 7. ID Definitions 50 10-25. Enter Secured OTP (ENSO). 50 10-26. Exit Secured OTP (EXSO). 50 10-27. Read Security Register (RDSCUR) 51			
10-21. Deep Power-down (DP)	10-21. Deep Power-down (DP) 46 10-22. Release from Deep Power-down (RDP), Read Electronic Signature (RES) 47 10-23. Read Electronic Manufacturer ID & Device ID (REMS), (REMS2), (REMS4) 49 10-24. ID Read 50 Table 7. ID Definitions 50 10-25. Enter Secured OTP (ENSO) 50 10-26. Exit Secured OTP (EXSO) 50 10-27. Read Security Register (RDSCUR) 51			
	10-22. Release from Deep Power-down (RDP), Read Electronic Signature (RES) 47 10-23. Read Electronic Manufacturer ID & Device ID (REMS), (REMS2), (REMS4) 49 10-24. ID Read 50 Table 7. ID Definitions 50 10-25. Enter Secured OTP (ENSO) 50 10-26. Exit Secured OTP (EXSO) 50 10-27. Read Security Register (RDSCUR) 51		• • •	
10-22. Release from Deep Power-down (RDP), Read Electronic Signature (RES)	10-23. Read Electronic Manufacturer ID & Device ID (REMS), (REMS2), (REMS4)			
	10-24. ID Read			
	Table 7. ID Definitions 50 10-25. Enter Secured OTP (ENSO) 50 10-26. Exit Secured OTP (EXSO) 50 10-27. Read Security Register (RDSCUR) 51			
	10-25. Enter Secured OTP (ENSO) .50 10-26. Exit Secured OTP (EXSO) .50 10-27. Read Security Register (RDSCUR) .51	10-24		
	10-26. Exit Secured OTP (EXSO)	10.25		
	10-27. Read Security Register (RDSCUR)			
	Iable S. Security Register Definition	10 21	Table 8. Security Register Definition	



	10-28.	Write Security Register (WRSCUR)	53
	10-29.	Write Protection Selection (WPSEL)	53
	10-30.	Single Block Lock/Unlock Protection (SBLK/SBULK)	57
	10-31.	Read Block Lock Status (RDBLOCK)	30
	10-32.	Gang Block Lock/Unlock (GBLK/GBULK)	31
	10-33.	Enable SO to Output RY/BY# (ESRY)	31
	10-34.	Disable SO to Output RY/BY# (DSRY)	31
		No Operation (NOP)	
	10-36.	Software Reset (Reset-Enable (RSTEN) and Reset (RST))	32
	10-37.	Read SFDP Mode (RDSFDP)	
		Table 9. Signature and Parameter Identification Data Values	
		Table 10. Parameter Table (0): JEDEC Flash Parameter Tables	
		Table 11. Parameter Table (1): Macronix Flash Parameter Tables	37
	-	R-ON STATE	-
12.		RICAL SPECIFICATIONS	
	12-1.	ABSOLUTE MAXIMUM RATINGS	70
		CAPACITANCE	
		DC CHARACTERISTICS	
		AC CHARACTERISTICS	
13.	TIMING	G ANALYSIS	′5
	13-1.	Power-Up Timing	77
14.	INITIA	L DELIVERY STATE	7
15.	OPER	ATING CONDITIONS	'8
16.	ERASI	E AND PROGRAMMING PERFORMANCE	30
17.	DATA	RETENTION	30
18.	LATCH	I-UP CHARACTERISTICS	30
19.	ORDE	RING INFORMATION	31
		NAME DESCRIPTION	
		ION HISTORY	-
-			



MX25L3255E

32M-BIT [x 1/x 2/x 4] CMOS MXSMIO[™] (SERIAL MULTI I/O) FLASH MEMORY

1. FEATURES

GENERAL

- Serial Peripheral Interface compatible -- Mode 0 and Mode 3
- 33,554,432 x 1 bit structure or 16,777,216 x 2 bits (two I/O mode) structure or 8,388,608 x 4 bits (four I/O mode) structure
- 1024 Equal Sectors with 4K bytes each - Any Sector can be erased individually
- · 128 Equal Blocks with 32K bytes each
- Any Block can be erased individually
- 64 Equal Blocks with 64K bytes each
 - Any Block can be erased individually
- Power Supply Operation
 - 2.7 to 3.6 volt for read, erase, and program operations
- Latch-up protected to 100mA from -1V to Vcc +1V

PERFORMANCE

- High Performance
 - VCC = 2.7~3.6V
 - Normal read
 - 50MHz
 - Fast read
 - 1 I/O: 104MHz with 8 dummy cycles
 - 2 I/O: 86MHz with 4 dummy cycles for 2READ instruction
 - 4 I/O: Up to 104MHz for 4READ instruction
 - Configurable dummy cycle number for 4READ operation
 - Fast program time: 1.4ms(typ.) and 5ms(max.)/page (256-byte per page)
 - Byte program time: 12us (typical)
 - Continuous Program mode (automatically increase address under word program mode)
 - Fast erase time: 60ms (typ.)/sector (4K-byte per sector); 0.7s(typ.) /block (64K-byte per block); 25s(typ.) / chip
- Low Power Consumption
 - Low active read current: 19mA(max.) at 104MHz, 10mA(max.) at 33MHz
 - Low active programming current: 25mA (max.)
 - Low active erase current: 25mA (max.)
 - Low standby current: 80uA (max.)
 - Deep power down current: 40uA (max.)
- Typical 100,000 erase/program cycles
- 20 years data retention



SOFTWARE FEATURES

- Input Data Format
 - 1-byte Command code
- Advanced Security Features
 - BP0-BP3 block group protect
 - Flexible individual block protect when OTP WPSEL=1
 - Additional 4K bits secured OTP for unique identifier
 - Permanent Lock
 - Read Protection function
- Auto Erase and Auto Program Algorithms
 - Automatically erases and verifies data at selected sector
 - Automatically programs and verifies data at selected page by an internal algorithm that automatically times the program pulse width (Any page to be programmed should have page in the erased state first.)
- Status Register Feature
- Electronic Identification
 - JEDEC 1-byte Manufacturer ID and 2-byte Device ID
 - RES command for 1-byte Device ID
 - The REMS, REMS2, REMS4 commands for 1-byte Manufacturer ID and 1-byte Device ID
- Support Serial Flash Discoverable Parameters (SFDP) mode

HARDWARE FEATURES

- SCLK Input
 - Serial clock input
- SI/SIO0
 - Serial Data Input or Serial Data Input/Output for 2 x I/O mode and 4 x I/O mode
- SO/SIO1
 - Serial Data Output or Serial Data Input/Output for 2 x I/O mode and 4 x I/O mode
- WP#/SIO2
 - Hardware write protection or serial data Input/Output for 4 x I/O mode
- HOLD#/SIO3
 - To pause the device without deselecting the device or serial data Input/Output for 4 x I/O mode
- PACKAGE
 - 8-pin SOP (200mil)
 - 24-ball TFBGA (6x8mm)
 - All devices are RoHS Compliant



2. GENERAL DESCRIPTION

MX25L3255E is 32Mb bits serial Flash memory, which is configured as 4,194,304 x 8 internally. When it is in two or four I/O mode, the structure becomes 16,777,216 bits x 2 or 8,388,608 bits x 4. MX25L3255E feature a serial peripheral interface and software protocol allowing operation on a simple 3-wire bus while it is in single I/O mode. The three bus signals are a clock input (SCLK), a serial data input (SI), and a serial data output (SO). Serial access to the device is enabled by CS# input.

MX25L3255E, MXSMIO[™] (Serial Multi I/O) flash memory, provides sequential read operation on whole chip and multi-I/O features.

When it is in dual I/O mode, the SI pin and SO pin become SIO0 pin and SIO1 pin for address/dummy bits input and data output. When it is in quad I/O mode, the SI pin, SO pin, WP# pin and HOLD# pin become SIO0 pin, SIO1 pin, SIO2 pin and SIO3 pin for address/dummy bits input and data Input/Output.

After program/erase command is issued, auto program/erase algorithms which program/erase and verify the specified page or sector/block locations will be executed. Program command is executed on byte basis, or page (256 bytes) basis, or word basis for Continuous Program mode, and erase command is executed on sector (4K-byte), block (32K-byte/64K-byte), or whole chip basis.

To provide user with ease of interface, a status register is included to indicate the status of the chip. The status read command can be issued to detect completion status of a program or erase operation via WIP bit.

When the device is not in operation and CS# is high, it is put in standby mode and draws less than 40uA DC current.

The MX25L3255E utilizes Macronix's proprietary memory cell, which reliably stores memory contents even after 100,000 program and erase cycles.

Numbers of Dummy Cycles	4 I/O
6	86*
8	104

 Table 1. Read Performance

Note: *means default status

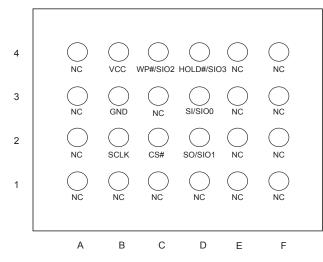


3. PIN CONFIGURATION

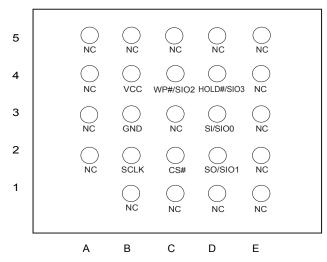
8-PIN SOP (200mil)



24-Ball TFBGA (6x8 mm, 4x6 Ball Array)



24-Ball TFBGA (6x8 mm, 5x5 Ball Array)



4. PIN DESCRIPTION

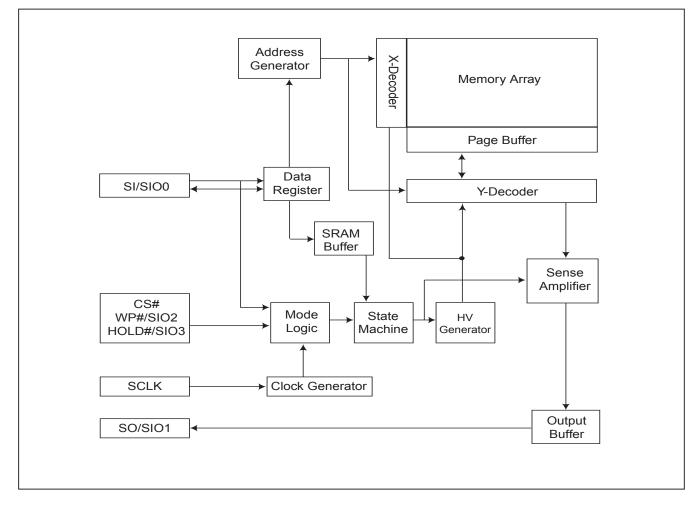
SYMBOL	DESCRIPTION
CS#	Chip Select
SI/SIO0	Serial Data Input (for 1xI/O)/ Serial Data Input & Output (for 2xI/O or 4xI/O mode)
SO/SIO1	Serial Data Output (for 1xI/O)/Serial Data Input & Output (for 2xI/O or 4xI/O mode)
SCLK	Clock Input
WP#/SIO2	Write protection: connect to GND or Serial Data Input & Output (for 4xI/O mode)
HOLD#/ SIO3	To pause the device without deselecting the device or Serial data Input/Output for 4 x I/O mode
VCC	+ 3.0V Power Supply
GND	Ground
NC	No Connection

Note:

1. The HOLD# pin is internal pull high.



5. BLOCK DIAGRAM





6. DATA PROTECTION

During power transition, there may be some false system level signals which result in inadvertent erasure or programming. The device is designed to protect itself from these accidental write cycles.

The state machine will be reset as standby mode automatically during power up. In addition, the control register architecture of the device constrains that the memory contents can only be changed after specific command sequences have completed successfully.

In the following, there are several features to protect the system from the accidental write cycles during VCC power-up and power-down or from system noise.

- Valid command length checking: The command length will be checked whether it is at byte base and completed on byte boundary.
- Write Enable (WREN) command: WREN command is required to set the Write Enable Latch bit (WEL) before other command to change data. The WEL bit will return to reset stage under following situation:
 - Power-up
 - Write Disable (WRDI) command completion
 - Write Status Register (WRSR) command completion
 - Page Program (PP, 4PP) command completion
 - Continuous Program mode (CP) instruction completion
 - Sector Erase (SE) command completion
 - Block Erase (BE, BE32K) command completion
 - Chip Erase (CE) command completion
 - Single Block Lock/Unlock (SBLK/SBULK) instruction completion
 - Gang Block Lock/Unlock (GBLK/GBULK) instruction completion
 - Permanent Lock (PLOCK) Instruction Completeion
 - Write Read Lock Register (WRLCR) Command Completion
- Deep Power Down Mode: By entering deep power down mode, the flash device also is under protected from writing all commands except Release from Deep Power Down mode command (RDP) and Read Electronic Signature command (RES).

I. Block lock protection

- The Software Protected Mode (SPM) uses (BP3, BP2, BP1, BP0) bits to allow part of memory to be protected as read only. The protected area definition is shown as table of *"Table 2. Protected Area Sizes"*, the protected areas are more flexible which may protect various areas by setting value of BP0-BP3 bits.

- The Hardware Protected Mode (HPM) uses WP#/SIO2 to protect the (BP3, BP2, BP1, BP0) bits and SRWD bit. If the system goes into four I/O mode, the feature of HPM will be disabled.

- MX25L3255E provides individual block (or sector) write protect & unprotect. User may enter the mode with WPSEL command and conduct individual block (or sector) write protect with SBLK instruction, or SBULK for individual block (or sector) unprotect. Under the mode, user may conduct whole chip (all blocks) protect with GBLK instruction and unlock the whole chip with GBULK instruction.



Table 2. Protected Area Sizes

Protected Area Sizes (T/B bit = 0)

Status bit				Protect Level		
BP3	BP2	BP1	BP0	32Mb		
0	0	0	0	0 (none)		
0	0	0	1	1 (1block, block 63rd)		
0	0	1	0	2 (2blocks, block 62nd-63rd)		
0	0	1	1	3 (4blocks, block 60th-63rd)		
0	1	0	0	4 (8blocks, block 56th-63rd)		
0	1	0	1	5 (16blocks, block 48th-63rd)		
0	1	1	0	6 (32blocks, block 32nd-63rd)		
0	1	1	1	7 (64blocks, protect all)		
1	0	0	0	8 (64blocks, protect all)		
1	0	0	1	9 (64blocks, protect all)		
1	0	1	0	10 (64blocks, protect all)		
1	0	1	1	11 (64blocks, protect all)		
1	1	0	0	12 (64blocks, protect all)		
1	1	0	1	13 (64blocks, protect all)		
1	1	1	0	14 (64blocks, protect all)		
1	1	1	1	15 (64blocks, protect all)		

Protected Area Sizes (T/B bit = 1)

Status bit				Protect Level		
BP3	BP2	BP1	BP0	32Mb		
0	0	0	0	0 (none)		
0	0	0	1	1 (1block, block 0th)		
0	0	1	0	2 (2blocks, block 0th-1st)		
0	0	1	1	3 (4blocks, block 0th-3rd)		
0	1	0	0	4 (8blocks, block 0th-7th)		
0	1	0	1	5 (16blocks, block 0th-15th)		
0	1	1	0	6 (32blocks, block 0th-31st)		
0	1	1	1	7 (64blocks, protect all)		
1	0	0	0	8 (64blocks, protect all)		
1	0	0	1	9 (64blocks, protect all)		
1	0	1	0	10 (64blocks, protect all)		
1	0	1	1	11 (64blocks, protect all)		
1	1	0	0	12 (64blocks, protect all)		
1	1	0	1	13 (64blocks, protect all)		
1	1	1	0	14 (64blocks, protect all)		
1	1	1	1	15 (64blocks, protect all)		

Note: The device is ready to accept a Chip Erase instruction if, and only if, all Block Protect (BP3, BP2, BP1, BP0) are 0.



II. Additional 4K-bit secured OTP for unique identifier: to provide 4K-bit One-Time Program area for setting device unique serial number - Which may be set by factory or system maker.

- Security register bit 0 indicates whether the chip is locked by factory or not.

- To program the 4K-bit secured OTP by entering 4K-bit secured OTP mode (with ENSO command), and going through normal program procedure, and then exiting 4K-bit secured OTP mode by writing EXSO command.

- Customer may lock-down the customer lockable secured OTP by writing WRSCUR(write security register) command to set customer lock-down bit1 as "1". Please refer to table of *"Table 8. Security Register Definition"* for security register bit definition and table of *"Table 3. 4K-bit Secured OTP Definition"* for address range definition.

Note: Once lock-down whatever by factory or customer, it cannot be changed any more. While in 4K-bit Secured OTP mode, array access is not allowed.

Table 3. 4K-bit Secured OTP Definition

Address range	Size	Standard Factory Lock	Customer Lock
xxx000~xxx00F	128-bit	ESN (electrical serial number)	Determined by systemer
xxx010~xxx1FF	3968-bit	N/A	Determined by customer



MX25L3255E

7. MEMORY ORGANIZATION

Table 4. Memory Organization

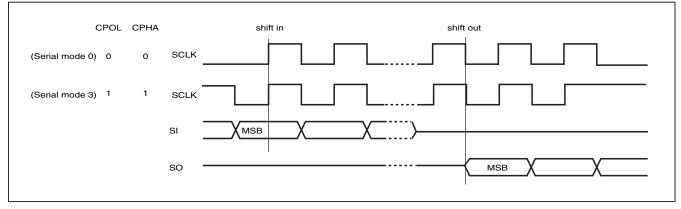
	Block(64K-byte)	Block(32K-byte)	Sector (4K-byte)	Address	Range	
			1023	3FF000h	3FFFFFh	
		127	÷			↓
			1016	3F8000h	3F8FFFh	individual 16 sectors
	63		1015	3F7000h	3F7FFFh	lock/unlock unit:4K-byte
		126	:			│ ▲
			1008	3F0000h	3F0FFFh	
			1007	3EF000h	3EFFFFh	·
		125	:			
	62		1000	3E8000h	3E8FFFh	
÷	02		999	3E7000h	3E7FFFh	
•		124				
individual block			992	3E0000h	3E0FFFh	
lock/unlock unit:64K-byte			991	3DF000h	3DFFFFh	
		123	:			
	61		984	3D8000h	3D8FFFh	
			983	3D7000h	3D7FFFh	
		122	:			
			976	3D0000h	3D0FFFh	
			47	02F000h	02FFFFh]
		5				†
	2		40	028000h	028FFFh	1
	2		39	027000h	027FFFh	
		4	:			ļ
individual block lock/unlock unit:64K-byte			32	020000h	020FFFh	
ioon/unioon unit.04m-byte			31	01F000h	01FFFFh	
A		3	:			
	1		24	018000h	018FFFh	
			23	017000h	017FFFh	
		2				
i			16	010000h	010FFFh	·
		1	15	00F000h	00FFFFh	
		1	:	000000		
	0		8 7	008000h 007000h	008FFFh 007FFFh	individual 16 sectors lock/unlock unit:4K-byte
	Ŭ	0	:	00700011	0076661	
		Ŭ	0	000000h	000FFFh	
	L	I	U	0000001	0001111	ii



8. DEVICE OPERATION

- 1. Before a command is issued, status register should be checked to ensure device is ready for the intended operation.
- 2. When incorrect command is inputted to this LSI, this LSI becomes standby mode and keeps the standby mode until next CS# falling edge. In standby mode, SO pin of this LSI should be High-Z.
- 3. When correct command is inputted to this LSI, this LSI becomes active mode and keeps the active mode until next CS# rising edge.
- 4. For standard single data rate serial mode, input data is latched on the rising edge of Serial Clock(SCLK) and data shifts out on the falling edge of SCLK. The difference of Serial mode 0 and mode 3 is shown as "Figure 1. Serial Modes Supported (for Normal Serial mode)".
- 5. For the following instructions: RDID, RDSR, RDSCUR, READ, FAST_READ, RDSFDP, 2READ, DREAD, 4READ, QREAD, RDBLOCK, RES, REMS, REMS2, REMS4, RDPLOCK, and RRLCR the shifted-in instruction sequence is followed by a data-out sequence. After any bit of data being shifted out, the CS# can be high. For the following instructions: WREN, WRDI, WRSR, SE, BE, BE32K, HPM, CE, PP, CP, 4PP, RDP, DP, WPSEL, SBLK, SBULK, GBULK, ENSO, EXSO, WRSCUR, ESRY, DSRY, PLOCK, and WRLCR, the CS# must go high exactly at the byte boundary; otherwise, the instruction will be rejected and not executed.
- 6. During the progress of Write Status Register, Program, Erase operation, to access the memory array is neglected and not affect the current operation of Write Status Register, Program, Erase.

Figure 1. Serial Modes Supported (for Normal Serial mode)



Note:

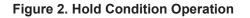
CPOL indicates clock polarity of Serial master, CPOL=1 for SCLK high while idle, CPOL=0 for SCLK low while not transmitting. CPHA indicates clock phase. The combination of CPOL bit and CPHA bit decides which Serial mode is supported.

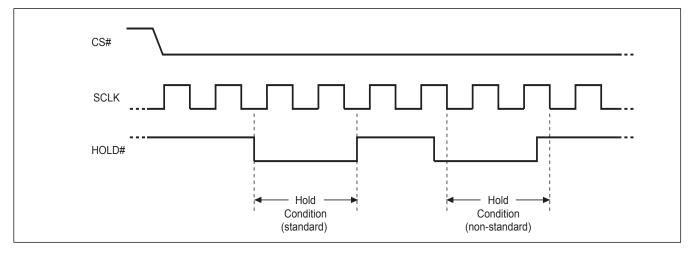


9. HOLD FEATURE

HOLD# pin signal goes low to hold any serial communications with the device. The HOLD feature will not stop the operation of write status register, programming, or erasing in progress.

The operation of HOLD requires Chip Select (CS#) keeping low and starts on falling edge of HOLD# pin signal while Serial Clock (SCLK) signal is being low (if Serial Clock signal is not being low, HOLD operation will not start until Serial Clock signal being low). The HOLD condition ends on the rising edge of HOLD# pin signal while Serial Clock(SCLK) signal is being low (if Serial Clock signal is not being low, HOLD operation will not end until Serial Clock being low).





The Serial Data Output (SO) is high impedance, both Serial Data Input (SI) and Serial Clock (SCLK) are don't care during the HOLD operation. If Chip Select (CS#) drives high during HOLD operation, it will reset the internal logic of the device. To re-start communication with chip, the HOLD# must be at high and CS# must be at low.

Note: The HOLD feature is disabled during Quad I/O mode.



10. COMMAND DESCRIPTION

Table 5. Command Sets

Read Commands

I/O	1	1	2	2	4	4	4
	READ	FAST READ	2READ	DREAD		4READ	
Command	(normal read)	(fast read	(2 x I/O read	(1I / 2O read	W4READ	(4 x I/O read	QREAD
	(normal read)	data)	command)	command)		command)	
1st byte	03 (hex)	0B (hex)	BB (hex)	3B (hex)	E7 (hex)	EB (hex)	6B (hex)
2nd byte	AD1(8)	AD1(8)	AD1(4)	AD1(8)	AD1(2)	AD1(2)	AD1(8)
3rd byte	AD2(8)	AD2(8)	AD2(4)	AD2(8)	AD2(2)	AD2(2)	AD2(8)
4th byte	AD3(8)	AD3(8)	AD3(4)	AD3(8)	AD3(2)	AD3(2)	AD3(8)
5th byte		Dummy(8)	Dummy(4)	Dummy(8)	Dummy(4)	Dummy*	Dummy(8)
	n bytes read	n bytes read	n bytes read		Quad I/O read	Quad I/O	
	out until CS#	out until CS#	out by 2 x I/O		with 4 dummy	read with	
Action	goes high	goes high	until CS# goes		cycles	configurable	
			high			dummy cycles	

Note: *Dummy cycle number will be different, depending on the bit7 (DC) setting of Configuration Register. Please refer to "*Configuration Register*" Table.



Other Commands

Command	WREN (write enable)	WRDI (write disable)	RDSR (read status register)	RDCR (read configuration register)	WRSR (write status/ configuration register)	4PP (quad page program)	SE (sector erase)
1st byte	06 (hex)	04 (hex)	05 (hex)	15 (hex)	01 (hex)	38 (hex)	20 (hex)
2nd byte					Values	AD1	AD1
3rd byte					Values	AD2	AD2
4th byte						AD3	AD3
Action	sets the (WEL) write enable latch bit	resets the (WEL) write enable latch bit	to read out the values of the status register	values of the	to write new values of the status register	quad input to program the selected page	to erase the selected sector

Command	BE 32K (block erase 32KB)	BE (block erase 64KB)	CE (chip erase)	PP (page program)	CP (continuous program)	DP (Deep power down)	RDP (Release from deep power down)
1st byte	52 (hex)	D8 (hex)	60 or C7 (hex)	02 (hex)	AD (hex)	B9 (hex)	AB (hex)
2nd byte	AD1	AD1		AD1	AD1		
3rd byte	AD2	AD2		AD2	AD2		
4th byte	AD3	AD3		AD3	AD3		
Action	to erase the selected 32KB block		to erase whole chip	to program the selected page		enters deep power down mode	release from deep power down mode

Command	RDID (read identific- ation)	RES (read electronic ID)	REMS (read electronic manufacturer & device ID)	REMS2 (read electronic manufacturer & device ID)	REMS4 (read electronic manufacturer & device ID)	ENSO (enter secured OTP)	EXSO (exit secured OTP)
1st byte	9F (hex)	AB (hex)	90 (hex)	EF (hex)	DF (hex)	B1 (hex)	C1 (hex)
2nd byte		х	х	х	х		
3rd byte		х	х	х	х		
4th byte		х	ADD (Note 2)	ADD	ADD		
Action	outputs JEDEC ID: 1-byte Manufacturer ID & 2-byte Device ID	to read out 1-byte Device ID	output the Manufacturer ID & Device ID	output the Manufacturer ID & Device ID	output the Manufacturer ID & device ID	to enter the 4K-bit secured OTP mode	to exit the 4K- bit secured OTP mode



Command	RDSCUR (read security register)	WRSCUR (write security register)	SBLK (single block lock	SBULK (single block unlock)	RDBLOCK (block protect read)	GBLK (gang block lock)	GBULK (gang block unlock)
1st byte	2B (hex)	2F (hex)	36 (hex)	39 (hex)	3C (hex)	7E (hex)	98 (hex)
2nd byte			AD1	AD1	AD1		
3rd byte			AD2	AD2	AD2		
4th byte			AD3	AD3	AD3		
Action	to read value of security register	to set the lock- down bit as "1" (once lock- down, cannot be update)	individual block (64K-byte) or sector (4K-byte) write protect	individual block (64K-byte) or sector (4K-byte) unprotect	read individual block or sector write protect status	whole chip write protect	whole chip unprotect

		DOTEN	RST	WPSEL	ESRY (enable	DSRY (disable	
Command	NOP (No Operation)	RSTEN (Reset Enable)	(Reset	(Write Protect	SO to output	SO to output	RDSFDP
	Operation)	(Reset Ellable)	Memory)	Selection)	RY/BY#)	RY/BY#)	
1st byte	00 (hex)	66 (hex)	99 (hex)	68 (hex)	70 (hex)	80 (hex)	5A (hex)
2nd byte							AD1
3rd byte							AD2
4th byte							AD3
5th byte							Dummy
Action				to enter	to enable SO	to disable SO	n bytes read
				and enable	to output RY/	to output RY/	out until CS#
				individal block	BY# during CP	BY# during CP	goes high
				protect mode	mode	mode	

Command	Release Read Enhanced	HPM (High Perform- ance Enable Mode)
1st byte	FF (hex)	A3 (hex)
2nd byte		
3rd byte		
4th byte		
5th byte		
Action	All these commands FFh, 00h, AAh or 55h will escape the performance mode	Quad I/O high Perform- ance mode

- Note 1: The count base is 4-bit for ADD(2) and Dummy(2) because of 2 x I/O. And the MSB is on SI/SIO1 which is different from 1 x I/O condition.
- Note 2: ADD=00H will output the manufacturer ID first and ADD=01H will output device ID first.
- Note 3: It is not recommended to adopt any other code not in the command definition table, which will potentially enter the hidden mode.
- Note 4: Before executing RST command, RSTEN command must be executed. If there is any other command to interfere, the reset operation will be disabled.



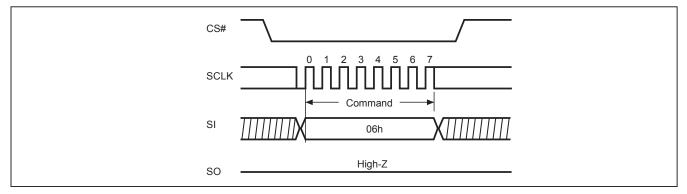
10-1. Write Enable (WREN)

The Write Enable (WREN) instruction is for setting Write Enable Latch (WEL) bit. For those instructions like PP, 4PP, CP, SE, BE, BE32K, CE, WRSR, WRSCUR, WPSEL, SBLK, SBULK, GBLK and GBULK, which are intended to change the device content, should be set every time after the WREN instruction setting the WEL bit.

The sequence of issuing WREN instruction is: CS# goes low \rightarrow sending WREN instruction code \rightarrow CS# goes high.

The SIO[3:1] are don't care in this mode.

Figure 3. Write Enable (WREN) Sequence (Command 06)





10-2. Write Disable (WRDI)

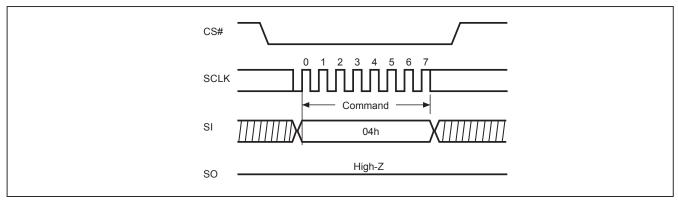
The Write Disable (WRDI) instruction is for resetting Write Enable Latch (WEL) bit.

The sequence of issuing WRDI instruction is: CS# goes low \rightarrow sending WRDI instruction code \rightarrow CS# goes high.

The WEL bit is reset by following situations:

- Power-up
- Write Disable (WRDI) instruction completion
- Write Status/Configuration Register (WRSR) instruction completion
- Page Program (PP, 4PP) instruction completion
- Sector Erase (SE) instruction completion
- Block Erase (BE, BE32K) instruction completion
- Chip Erase (CE) instruction completion
- Continuous Program mode (CP) instruction completion
- Single Block Lock/Unlock (SBLK/SBULK) instruction completion
- Gang Block Lock/Unlock (GBLK/GBULK) instruction completion

Figure 4. Write Disable (WRDI) Sequence (Command 04)





10-3. Read Identification (RDID)

The RDID instruction is for reading the Manufacturer ID of 1-byte and followed by Device ID of 2-byte. The Macronix Manufacturer ID is C2(hex), the memory type ID is 9E(hex) as the first-byte Device ID, and the individual Device ID of second-byte ID are listed as table of *"Table 7. ID Definitions"*.

The sequence of issuing RDID instruction is: CS# goes low \rightarrow sending RDID instruction code \rightarrow 24-bits ID data out on SO \rightarrow to end RDID operation can use CS# to high at any time during data out.

While Program/Erase operation is in progress, it will not decode the RDID instruction, so there's no effect on the cycle of program/erase operation which is currently in progress. When CS# goes high, the device is at standby stage.

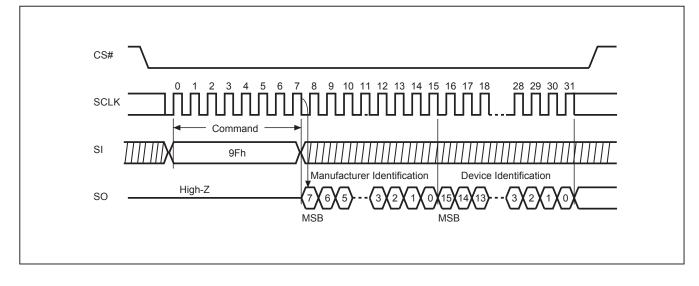


Figure 5. Read Identification (RDID) Sequence (Command 9F)



10-4. Read Status Register (RDSR)

The RDSR instruction is for reading Status Register. The Read Status Register can be read at any time (even in program/erase/write status register condition) and continuously. It is recommended to check the Write in Progress (WIP) bit before sending a new instruction when a program, erase, or write status register operation is in progress.

The sequence of issuing RDSR instruction is: CS# goes low \rightarrow sending RDSR instruction code \rightarrow Status Register data out on SO.

The SIO[3:1] are don't care when during this mode.

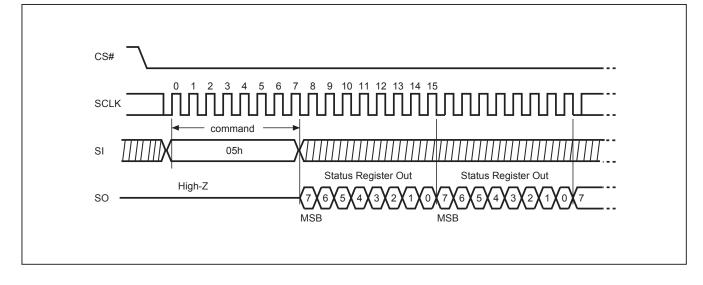


Figure 6. Read Status Register (RDSR) Sequence (Command 05)



The definition of the status register bits is as below:

WIP bit. The Write in Progress (WIP) bit, a volatile bit, indicates whether the device is busy in program/erase/ write status register progress. When WIP bit sets to 1, which means the device is busy in program/erase/write status register progress. When WIP bit sets to 0, which means the device is not in progress of program/erase/ write status register cycle.

WEL bit. The Write Enable Latch (WEL) bit, a volatile bit, indicates whether the device is set to internal write enable latch. When WEL bit sets to "1", which means the internal write enable latch is set, the device can accept program/erase/write status register instruction. When WEL bit sets to 0, which means no internal write enable latch; the device will not accept program/erase/write status register instruction. The program/erase command will be ignored and will reset WEL bit if it is applied to a protected memory area. To ensure both WIP bit & WEL bit are both set to 0 and available for next program/erase/operations, WIP bit needs to be confirm to be 0 before polling WEL bit. After WIP bit confirmed, WEL bit needs to be confirm to be 0.

BP3, BP2, BP1, BP0 bits. The Block Protect (BP3, BP2, BP1, BP0) bits, non-volatile bits, indicate the protected area (as defined in *"Table 2. Protected Area Sizes"*) of the device to against the program/erase instruction without hardware protection mode being set. To write the Block Protect (BP3, BP2, BP1, BP0) bits requires the Write Status Register (WRSR) instruction to be executed. Those bits define the protected area of the memory to against Page Program (PP), Sector Erase (SE), Block Erase (BE) and Chip Erase (CE) instructions (only if all Block Protect bits set to 0, the CE instruction can be executed). The BP3, BP2, BP1, BP0 bits are "0" as default. Which is un-protected.

QE bit. The Quad Enable (QE) bit, non-volatile bit, while it is "0" (factory default), it performs non-Quad and WP# is enable. While QE is "1", it performs Quad I/O mode and WP# is disabled. In the other word, if the system goes into four I/O mode (QE=1), the feature of HPM will be disabled.

SRWD bit. The Status Register Write Disable (SRWD) bit, non-volatile bit, default value is "0". SRWD bit is operated together with Write Protection (WP#/SIO2) pin for providing hardware protection mode. The hardware protection mode requires SRWD sets to 1 and WP#/SIO2 pin signal is low stage. In the hardware protection mode, the Write Status Register (WRSR) instruction is no longer accepted for execution and the SRWD bit and Block Protect bits (BP3, BP2, BP1, BP0) are read only. The SRWD bit defaults to be "0".

bit7	bit6	bit5	bit4	bit3	bit2	bit1	bit0
SRWD (status register write protect)	QE (Quad Enable)	BP3 (level of protected block)	BP2 (level of protected block)	BP1 (level of protected block)	BP0 (level of protected block)	WEL (write enable latch)	WIP (write in progress bit)
1=status register write disable	1= Quad Enable 0=not Quad Enable	(note 1)	(note 1)	(note 1)	(note 1)	1=write enable 0=not write enable	1=write operation 0=not in write operation
Non-volatile bit	Non-volatile bit	Non-volatile bit	Non-volatile bit	Non-volatile bit	Non-volatile bit	volatile bit	volatile bit

Status Register

Note: see the "Table 2. Protected Area Sizes" .



Configuration Register

The Configuration Register is able to change the default status of Flash memory. Flash memory will be configured after the CR bit is set.

TB bit

The Top/Bottom (TB) bit is a non-volatile OTP bit. The Top/Bottom (TB) bit is used to configure the Block Protect area by BP bit (BP3, BP2, BP1, BP0), starting from TOP or Bottom of the memory array. The TB bit is defaulted as "0", which means Top area protect. When it is set as "1", the protect area will change to Bottom area of the memory device. To write the TB bit requires the Write Status Register (WRSR) instruction to be executed.

Configuration Register

bit7	bit6	bit5	bit4	bit3	bit2	bit1	bit0
DC				TB			
(Dummy	Reserved	Reserved	Reserved	(top/bottom	Reserved	Reserved	Reserved
Cycle)				selected)			
				0=Top area			
				protect			
(Note)	Х	Х	Х	1=Bottom	Х	х	х
				area protect			
				(Default=0)			
Volatile bit	Х	х	х	OTP	Х	x	x

Note: See "Dummy Cycle and Frequency Table", with "Don't Care" on other Reserved Configuration Registers.

Dummy Cycle and Frequency Table

DC	Numbers of Dummy clock cycles	Quad I/O Fast Read	
1	8	104	
0 (default)	6	86	



10-5. Write Status Register (WRSR)

The WRSR instruction is for changing the values of Status Register Bits and Configuration Register Bits. Before sending WRSR instruction, the Write Enable (WREN) instruction must be decoded and executed to set the Write Enable Latch (WEL) bit in advance. The WRSR instruction can change the value of Block Protect (BP3, BP2, BP1, BP0) bits to define the protected area of memory (as shown in *"Table 2. Protected Area Sizes"*). The WRSR also can set or reset the Quad enable (QE) bit and set or reset the Status Register Write Disable (SRWD) bit in accordance with Write Protection (WP#/SIO2) pin signal, but has no effect on bit1(WEL) and bit0 (WIP) of the status register. The WRSR instruction cannot be executed once the Hardware Protected Mode (HPM) is entered.

The sequence of issuing WRSR instruction is: CS# goes low \rightarrow sending WRSR instruction code \rightarrow Status Register data on SI \rightarrow CS# goes high.

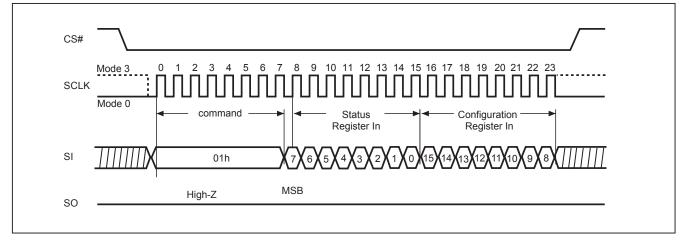


Figure 7. Write Status Register (WRSR) Sequence (Command 01)



The CS# must go high exactly at the byte boundary; otherwise, the instruction will be rejected and not executed. The self-timed Write Status Register cycle time (tW) is initiated as soon as Chip Select (CS#) goes high. The Write in Progress (WIP) bit still can be checked out during the Write Status Register cycle is in progress. The WIP sets 1 during the tW timing, and sets 0 when Write Status Register Cycle is completed, and the Write Enable Latch (WEL) bit is reset.

Table 6. Protection Modes

Mode	Status register condition	WP# and SRWD bit status	Memory
Software protection mode (SPM)	Status register can be written in (WEL bit is set to "1") and the SRWD, BP0-BP3 bits can be changed	WP#=1 and SRWD bit=0, or WP#=0 and SRWD bit=0, or WP#=1 and SRWD=1	I DO DIOTOCION SIGS CONDO
Hardware protection mode (HPM)	The SRWD, BP0-BP3 of status register bits cannot be changed	WP#=0, SRWD bit=1	The protected area cannot be programmed or erased.

Note: As defined by the values in the Block Protect (BP3, BP2, BP1, BP0) bits of the Status Register, as shown in *"Table 2. Protected Area Sizes"*.

As the table above showing, the summary of the Software Protected Mode (SPM) and Hardware Protected Mode (HPM):

Software Protected Mode (SPM):

- When SRWD bit=0, no matter WP#/SIO2 is low or high, the WREN instruction may set the WEL bit and can change the values of SRWD, BP3, BP2, BP1, BP0. The protected area, which is defined by BP3, BP2, BP1, BP0, is at software protected mode (SPM).
- When SRWD bit=1 and WP#/SIO2 is high, the WREN instruction may set the WEL bit can change the values of SRWD, BP3, BP2, BP1, BP0. The protected area, which is defined by BP3, BP2, BP1, BP0, is at software protected mode (SPM)

Hardware Protected Mode (HPM):

 When SRWD bit=1, and then WP#/SIO2 is low (or WP#/SIO2 is low before SRWD bit=1), it enters the hardware protected mode (HPM). The data of the protected area is protected by software protected mode by BP3, BP2, BP1, BP0 and hardware protected mode by the WP#/SIO2 to against data modification.

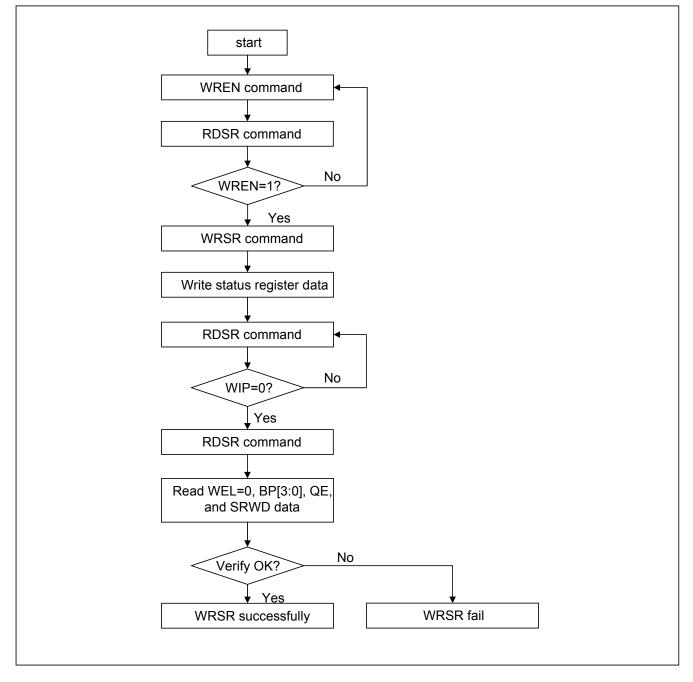
Note:

To exit the hardware protected mode requires WP#/SIO2 driving high once the hardware protected mode is entered. If the WP#/SIO2 pin is permanently connected to high, the hardware protected mode can never be entered; only can use software protected mode via BP3, BP2, BP1, BP0.

If the system goes into four I/O mode, the feature of HPM will be disabled.



Figure 8. WRSR flow





10-6. Read Data Bytes (READ)

The read instruction is for reading data out. The address is latched on rising edge of SCLK, and data shifts out on the falling edge of SCLK at a maximum frequency fR. The first address byte can be at any location. The address is automatically increased to the next higher address after each byte data is shifted out, so the whole memory can be read out at a single READ instruction. The address counter rolls over to 0 when the highest address has been reached.

The sequence of issuing READ instruction is: CS# goes low \rightarrow sending READ instruction code \rightarrow 3-byte address on SI \rightarrow data out on SO \rightarrow to end READ operation can use CS# to high at any time during data out.

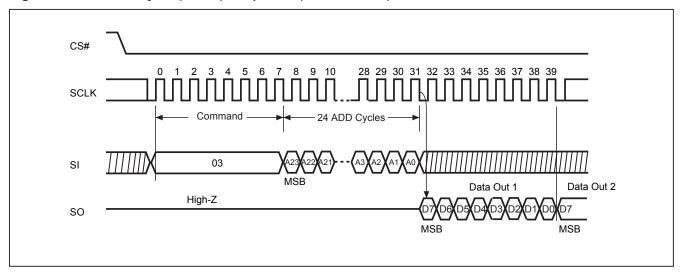


Figure 9. Read Data Bytes (READ) Sequence (Command 03)



10-7. Read Data Bytes at Higher Speed (FAST_READ)

The FAST_READ instruction is for quickly reading data out. The address is latched on rising edge of SCLK, and data of each bit shifts out on the falling edge of SCLK at a maximum frequency fC. The first address byte can be at any location. The address is automatically increased to the next higher address after each byte data is shifted out, so the whole memory can be read out at a single FAST_READ instruction. The address counter rolls over to 0 when the highest address has been reached.

The sequence of issuing FAST_READ instruction is: CS# goes low \rightarrow sending FAST_READ instruction code \rightarrow 3-byte address on SI \rightarrow 1-dummy byte (default) address on SI \rightarrow data out on SO \rightarrow to end FAST_READ operation can use CS# to high at any time during data out.

While Program/Erase/Write Status Register cycle is in progress, FAST_READ instruction is rejected without any impact on the Program/Erase/Write Status Register current cycle.

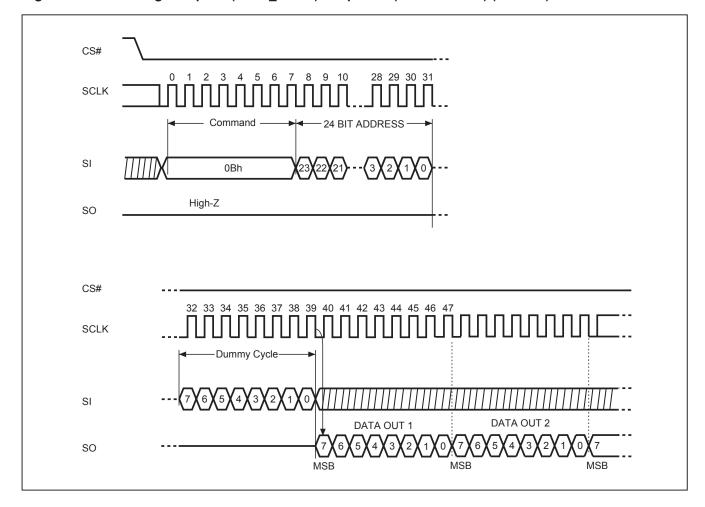


Figure 10. Read at Higher Speed (FAST_READ) Sequence (Command 0B) (104MHz)



10-8. Dual Read Mode (DREAD)

The DREAD instruction enable double throughput of Serial Flash in read mode. The address is latched on rising edge of SCLK, and data of every two bits (interleave on 2 I/O pins) shift out on the falling edge of SCLK at a maximum frequency fT. The first address byte can be at any location. The address is automatically increased to the next higher address after each byte data is shifted out, so the whole memory can be read out at a single DREAD instruction. The address counter rolls over to 0 when the highest address has been reached. Once writing DREAD instruction, the following data out will perform as 2-bit instead of previous 1-bit.

The sequence of issuing DREAD instruction is: CS# goes low \rightarrow sending DREAD instruction \rightarrow 3-byte address on SI \rightarrow 8-bit dummy cycle \rightarrow data out interleave on SO1 & SO0 \rightarrow to end DREAD operation can use CS# to high at any time during data out.

While Program/Erase/Write Status Register cycle is in progress, DREAD instruction is rejected without any impact on the Program/Erase/Write Status Register current cycle.

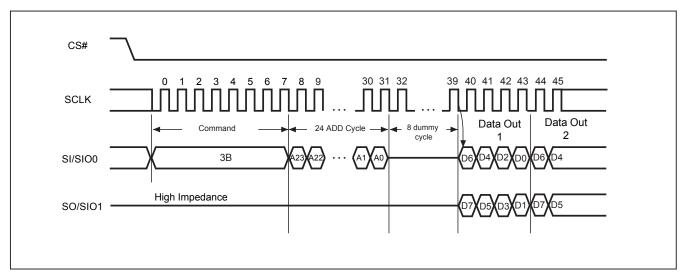


Figure 11. Dual Read Mode Sequence (Command 3B)

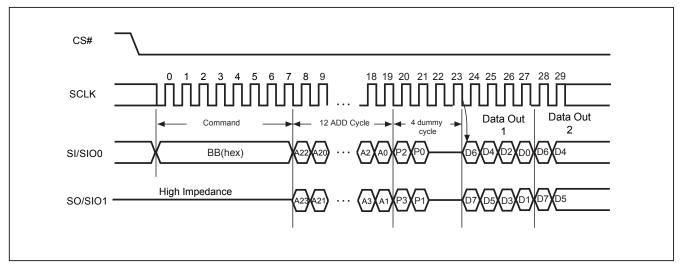


10-9. 2 x I/O Read Mode (2READ)

The 2READ instruction enables Double Transfer Rate of Serial Flash in read mode. The address is latched on rising edge of SCLK, and data of every two bits (interleave on 2 I/O pins) shift out on the falling edge of SCLK at a maximum frequency fT. The first address byte can be at any location. The address is automatically increased to the next higher address after each byte data is shifted out, so the whole memory can be read out at a single 2READ instruction. The address counter rolls over to 0 when the highest address has been reached. Once writing 2READ instruction, the following address/dummy/data out will perform as 2-bit instead of previous 1-bit.

The sequence of issuing 2READ instruction is: CS# goes low \rightarrow sending 2READ instruction \rightarrow 24-bit address interleave on SIO1 & SIO0 \rightarrow 4-bit dummy cycle on SIO1 & SIO0 \rightarrow data out interleave on SIO1 & SIO0 \rightarrow to end 2READ operation can use CS# to high at any time during data out.

While Program/Erase/Write Status Register cycle is in progress, 2READ instruction is rejected without any impact on the Program/Erase/Write Status Register current cycle.





Note: SI/SIO0 or SO/SIO1 should be kept "0h" or "Fh" in the first two dummy cycles. In other words, P2=P0 or P3=P1 is necessary.



10-10. Quad Read Mode (QREAD)

The QREAD instruction enable quad throughput of Serial Flash in read mode. The address is latched on rising edge of SCLK, and data of every four bits (interleave on 4 I/O pins) shift out on the falling edge of SCLK at a maximum frequency fQ. The first address byte can be at any location. The address is automatically increased to the next higher address after each byte data is shifted out, so the whole memory can be read out at a single QREAD instruction. The address counter rolls over to 0 when the highest address has been reached. Once writing QREAD instruction, the following data out will perform as 4-bit instead of previous 1-bit.

The sequence of issuing QREAD instruction is: CS# goes low \rightarrow sending QREAD instruction \rightarrow 3-byte address on SI \rightarrow 8-bit dummy cycle \rightarrow data out interleave on SO3, SO2, SO1 & SO0 \rightarrow to end QREAD operation can use CS# to high at any time during data out.

While Program/Erase/Write Status Register cycle is in progress, QREAD instruction is rejected without any impact on the Program/Erase/Write Status Register current cycle.

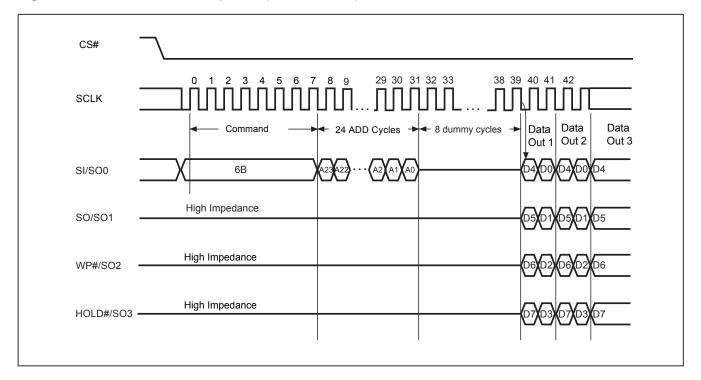


Figure 13. Quad Read Mode Sequence (Command 6B)

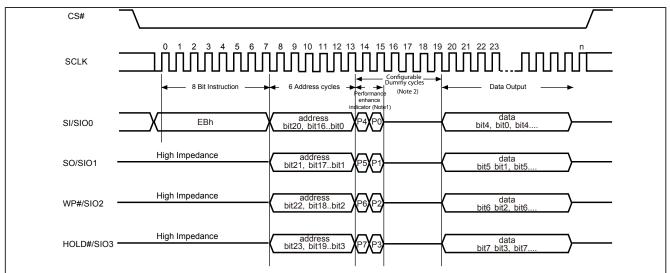


10-11. 4 x I/O Read Mode (4READ)

The 4READ instruction enables quad throughput of Serial Flash in read mode. A Quad Enable (QE) bit of status Register must be set to "1" before sending the 4READ instruction. The address is latched on rising edge of SCLK, and data of every four bits (interleave on 4 I/O pins) shift out on the falling edge of SCLK at a maximum frequency fQ. The first address byte can be at any location. The address is automatically increased to the next higher address after each byte data is shifted out, so the whole memory can be read out at a single 4READ instruction. The address counter rolls over to 0 when the highest address has been reached. Once writing 4READ instruction, the following address/dummy/data out will perform as 4-bit instead of previous 1-bit.

The sequence of issuing 4READ instruction is: CS# goes low \rightarrow sending 4READ instruction \rightarrow 24-bit address interleave on SIO3, SIO2, SIO1 & SIO0 \rightarrow 2+4 dummy cycles (default) \rightarrow data out interleave on SIO3, SIO2, SIO1 & SIO0 \rightarrow to end 4READ operation can use CS# to high at any time during data out.

W4READ instruction (E7) is also available for 4 I/O read. The sequence is similar to 4READ, but with only 4 dummy cycles. The clock rate runs at 54MHz.





Note:

- 1. Hi-impedance is inhibited for the two clock cycles.
- 2. P7≠P3, P6≠P2, P5≠P1 & P4≠P0 (Toggling) is inhibited.
- 3. The Configurable Dummy Cycle is set by Configuration Register Bit. Please see "Dummy Cycle and Frequency Table"



Another sequence of issuing 4READ instruction especially useful in random access is : CS# goes low \rightarrow sending 4READ instruction \rightarrow 3-bytes address interleave on SIO3, SIO2, SIO1 & SIO0 \rightarrow performance enhance toggling bit P[7:0] \rightarrow 4 dummy cycles (default) \rightarrow data out still CS# goes high \rightarrow CS# goes low (reduce 4READ instruction) \rightarrow 24-bit random access address (Please refer to *"Figure 15. 4 x I/O Read Enhance Performance Mode Sequence (Command EB)"*).

In the performance-enhancing mode (Notes of *"Figure 15. 4 x I/O Read Enhance Performance Mode Sequence (Command EB)"*), P[7:4] must be toggling with P[3:0]; likewise P[7:0]=A5h, 5Ah, F0h or 0Fh can make this mode continue and reduce the next 4READ instruction. Once P[7:4] is no longer toggling with P[3:0]; likewise P[7:0]=FFh, 00h, AAh or 55h. These commands will reset the performance enhance mode. And afterwards CS# is raised and then lowered, the system then will return to normal operation.

While Program/Erase/Write Status Register cycle is in progress, 4READ instruction is rejected without any impact on the Program/Erase/Write Status Register current cycle.

10-12. Performance Enhance Mode

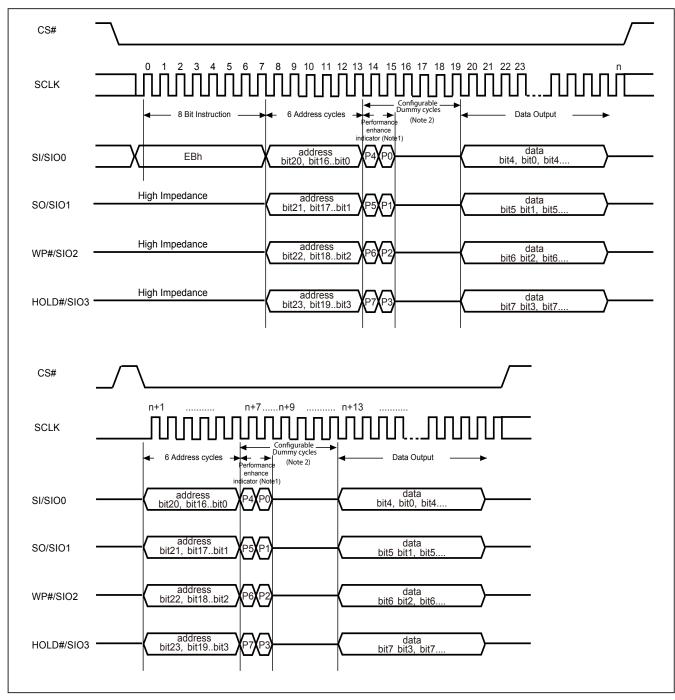
The device could waive the command cycle bits if the two cycle bits after address cycle toggles. (Please note *"Figure 15. 4 x I/O Read Enhance Performance Mode Sequence (Command EB)"*)

Please be noticed that "EBh" and "E7h" commands support enhance mode. The performance enhance mode is not supported in dual I/O mode.

After entering enhance mode, following CSB go high, the device will stay in the read mode and treat CSB go low of the first clock as address instead of command cycle.

To exit enhance mode, a new fast read command whose first two dummy cycles is not toggle then exit. Or issue "FFh" command to exit enhance mode.







Note:

- 1. Performance enhance mode, if P7≠P3 & P6≠P2 & P5≠P1 & P4≠P0 (Toggling), ex: A5, 5A, 0F, if not using performance enhance recommend to keep 1 or 0 in performance enhance indicator. Reset the performance enhance mode, if P7=P3 or P6=P2 or P5=P1 or P4=P0, ex: AA, 00, FF
- The Configurable Dummy Cycle is set by Configuration Register Bit. Please see "Dummy Cycle and Frequency Table"



10-13. Performance Enhance Mode Reset (FFh)

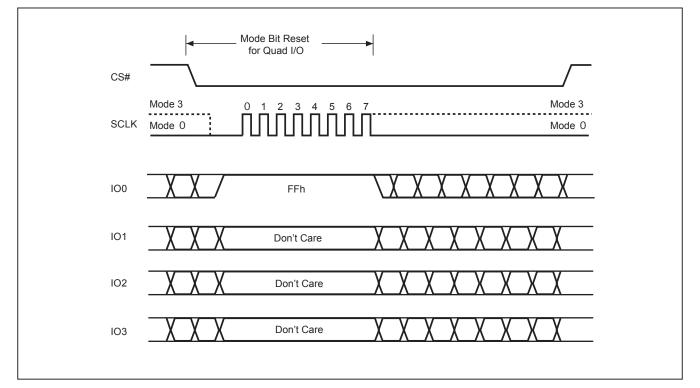
To conduct the Performance Enhance Mode Reset operation, FFh command code, 8 clocks, should be issued in 1I/O sequence.

If the system controller is being Reset during operation, the flash device will return to the standard operation.

Upon Reset of main chip, Instruction would be issued from the system. Instructions like Read ID (9Fh) or Fast Read (0Bh) would be issued.

The SIO[3:1] are don't care when during this mode.







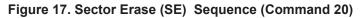
10-14. Sector Erase (SE)

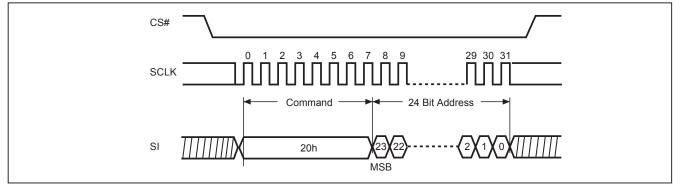
The Sector Erase (SE) instruction is for erasing the data of the chosen sector to be "1". The instruction is used for any 4K-byte sector. A Write Enable (WREN) instruction must execute to set the Write Enable Latch (WEL) bit before sending the Sector Erase (SE). Any address of the sector (see *"Table 4. Memory Organization"*) is a valid address for Sector Erase (SE) instruction. The CS# must go high exactly at the byte boundary (the latest eighth of address byte has been latched-in); otherwise, the instruction will be rejected and not executed.

The sequence of issuing SE instruction is: CS# goes low \rightarrow sending SE instruction code \rightarrow 3-byte address on SI \rightarrow CS# goes high.

The SIO[3:1] are don't care when during this mode.

The self-timed Sector Erase Cycle time (tSE) is initiated as soon as Chip Select (CS#) goes high. The Write in Progress (WIP) bit still can be checked out during the Sector Erase cycle is in progress. The WIP sets 1 during the tSE timing, and sets 0 when Sector Erase Cycle is completed, and the Write Enable Latch (WEL) bit is reset. If the sector is protected by BP3~0 (WPSEL=0) or by individual lock/permanent lock (WPSEL=1), the array data will be protected (no change) and the WEL bit still be reset.







10-15. Block Erase (BE)

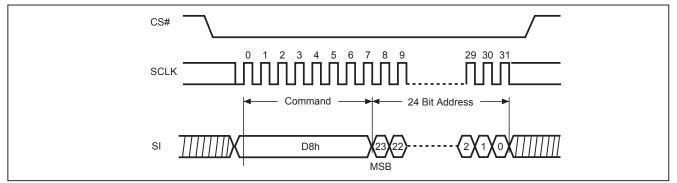
The Block Erase (BE) instruction is for erasing the data of the chosen block to be "1". The instruction is used for 64K-byte block erase operation. A Write Enable (WREN) instruction must execute to set the Write Enable Latch (WEL) bit before sending the Block Erase (BE). Any address of the block (see "*Table 4. Memory Organization*") is a valid address for Block Erase (BE) instruction. The CS# must go high exactly at the byte boundary (the latest eighth of address byte has been latched-in); otherwise, the instruction will be rejected and not executed.

The sequence of issuing BE instruction is: CS# goes low \rightarrow sending BE instruction code \rightarrow 3-byte address on SI \rightarrow CS# goes high.

The SIO[3:1] are don't care when during this mode.

The self-timed Block Erase Cycle time (tBE) is initiated as soon as Chip Select (CS#) goes high. The Write in Progress (WIP) bit still can be checked out during the Sector Erase cycle is in progress. The WIP sets 1 during the tBE timing, and sets 0 when Sector Erase Cycle is completed, and the Write Enable Latch (WEL) bit is reset. If the block is protected by BP3~0 (WPSEL=0) or by individual lock/permanent lock (WPSEL=1), the array data will be protected (no change) and the WEL bit still be reset.

Figure 18. Block Erase (BE) Sequence (Command D8)





10-16. Block Erase (BE32K)

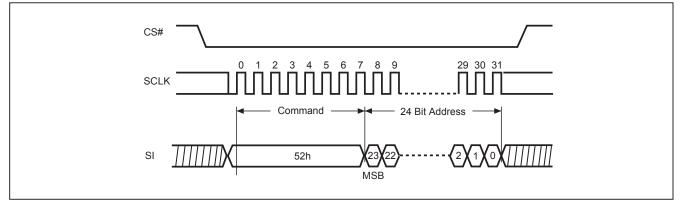
The Block Erase (BE32) instruction is for erasing the data of the chosen block to be "1". The instruction is used for 32K-byte block erase operation. A Write Enable (WREN) instruction must execute to set the Write Enable Latch (WEL) bit before sending the Block Erase (BE32). Any address of the block (see *"Table 4. Memory Organization"*) is a valid address for Block Erase (BE32) instruction. The CS# must go high exactly at the byte boundary (the latest eighth of address byte has been latched-in); otherwise, the instruction will be rejected and not executed.

The sequence of issuing BE32 instruction is: CS# goes low \rightarrow sending BE32 instruction code \rightarrow 3-byte address on SI \rightarrow CS# goes high.

The SIO[3:1] are don't care when during this mode.

The self-timed Block Erase Cycle time (tBE) is initiated as soon as Chip Select (CS#) goes high. The Write in Progress (WIP) bit still can be checked out during the Sector Erase cycle is in progress. The WIP sets 1 during the tBE timing, and sets 0 when Sector Erase Cycle is completed, and the Write Enable Latch (WEL) bit is reset. If the block is protected by BP3~0 (WPSEL=0) or by individual lock/permanent lock (WPSEL=1), the array data will be protected (no change) and the WEL bit still be reset.







10-17. Chip Erase (CE)

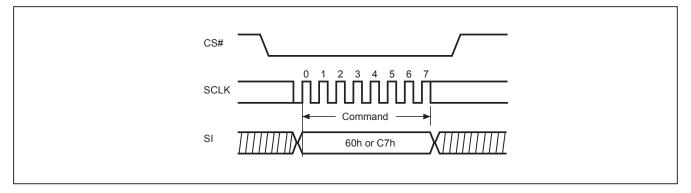
The Chip Erase (CE) instruction is for erasing the data of the whole chip to be "1". A Write Enable (WREN) instruction must execute to set the Write Enable Latch (WEL) bit before sending the Chip Erase (CE). The CS# must go high exactly at the byte boundary; otherwise, the instruction will be rejected and not executed.

The sequence of issuing CE instruction is: CS# goes low \rightarrow sending CE instruction code \rightarrow CS# goes high.

The SIO[3:1] are don't care when during this mode.

The self-timed Chip Erase Cycle time (tCE) is initiated as soon as Chip Select (CS#) goes high. The Write in Progress (WIP) bit still can be checked out during the Chip Erase cycle is in progress. The WIP sets 1 during the tCE timing, and sets 0 when Chip Erase Cycle is completed, and the Write Enable Latch (WEL) bit is reset. If the chip is protected the Chip Erase (CE) instruction will not be executed, but WEL will be reset.

Figure 20. Chip Erase (CE) Sequence (Command 60 or C7)





10-18. Page Program (PP)

The Page Program (PP) instruction is for programming the memory to be "0". A Write Enable (WREN) instruction must execute to set the Write Enable Latch (WEL) bit before sending the Page Program (PP). The device programs only the last 256 data bytes sent to the device. If the entire 256 data bytes are going to be programmed, A7-A0 (The eight least significant address bits) should be set to 0. If the eight least significant address bits (A7-A0) are not all 0, all transmitted data going beyond the end of the current page are programmed from the start address of the same page (from the address A7-A0 are all 0). If more than 256 bytes are sent to the device, the data of the last 256-byte is programmed at the request page and previous data will be disregarded. If less than 256 bytes are sent to the device, the data is programmed at the requested address of the page without effect on other address of the same page.

The sequence of issuing PP instruction is: CS# goes low \rightarrow sending PP instruction code \rightarrow 3-byte address on SI \rightarrow at least 1-byte on data on SI \rightarrow CS# goes high.

The CS# must be kept to low during the whole Page Program cycle; The CS# must go high exactly at the byte boundary (the latest eighth bit of data being latched in), otherwise, the instruction will be rejected and will not be executed.

The self-timed Page Program Cycle time (tPP) is initiated as soon as Chip Select (CS#) goes high. The Write in Progress (WIP) bit still can be checked out during the Page Program cycle is in progress. The WIP sets 1 during the tPP timing, and sets 0 when Page Program Cycle is completed, and the Write Enable Latch (WEL) bit is reset. If the page is protected by BP3~0 (WPSEL=0) or by individual lock/permanent lock (WPSEL=1), the array data will be protected (no change) and the WEL bit will still be reset.

The SIO[3:1] are don't care when during this mode.

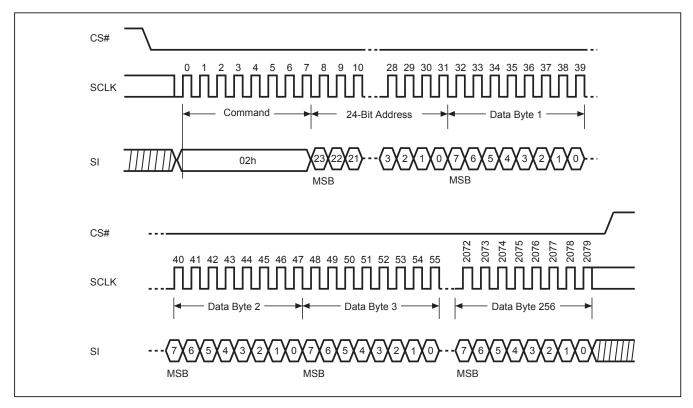


Figure 21. Page Program (PP) Sequence (Command 02)



10-19. 4 x I/O Page Program (4PP)

The Quad Page Program (4PP) instruction is for programming the memory to be "0". A Write Enable (WREN) instruction must execute to set the Write Enable Latch (WEL) bit and Quad Enable (QE) bit must be set to "1" before sending the Quad Page Program (4PP). The Quad Page Programming takes four pins: SIO0, SIO1, SIO2, and SIO3, which can raise programmer performance and the effectiveness of application of lower clock less than 85MHz. For system with faster clock, the Quad page program cannot provide more actual favors, because the required internal page program time is far more than the time data flows in. Therefore, we suggest that while executing this command (especially during sending data), user can slow the clock speed down to 85MHz below. The other function descriptions are as same as standard page program.

The sequence of issuing 4PP instruction is: CS# goes low \rightarrow sending 4PP instruction code \rightarrow 3-byte address on SIO[3:0] \rightarrow at least 1-byte on data on SIO[3:0] \rightarrow CS# goes high.

If the page is protected by BP3~0 (WPSEL=0) or by individual lock/permanent lock (WPSEL=1), the array data will be protected (no change) and the WEL bit will still be reset.

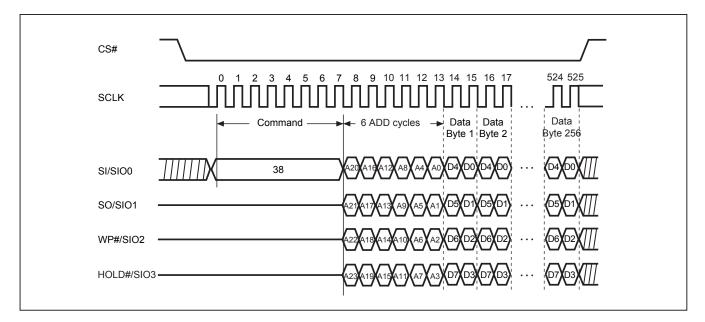


Figure 22. 4 x I/O Page Program (4PP) Sequence (Command 38)



The Program/Erase function instruction function flow is as follows:

Figure 23. Program/Erase Flow(1) with read array data

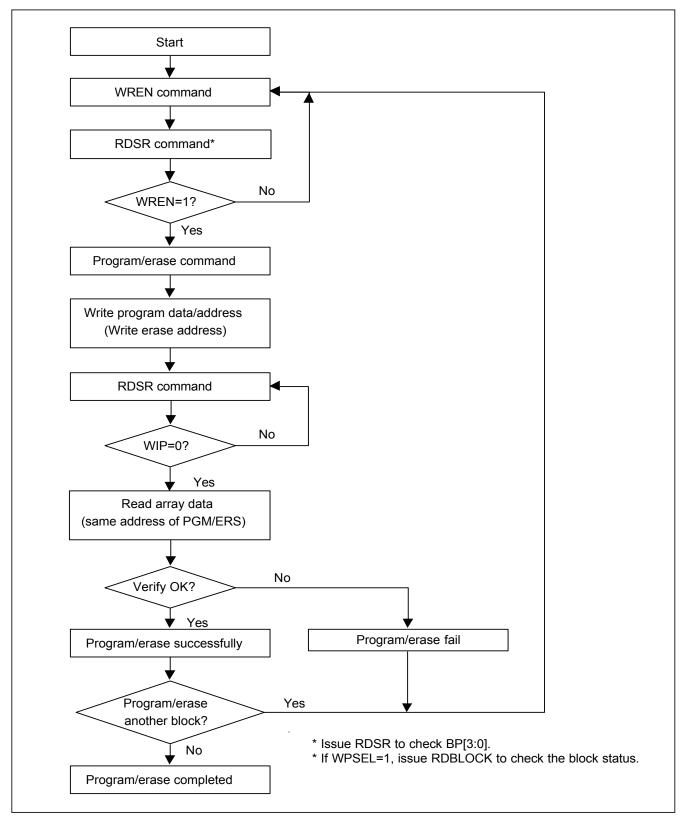
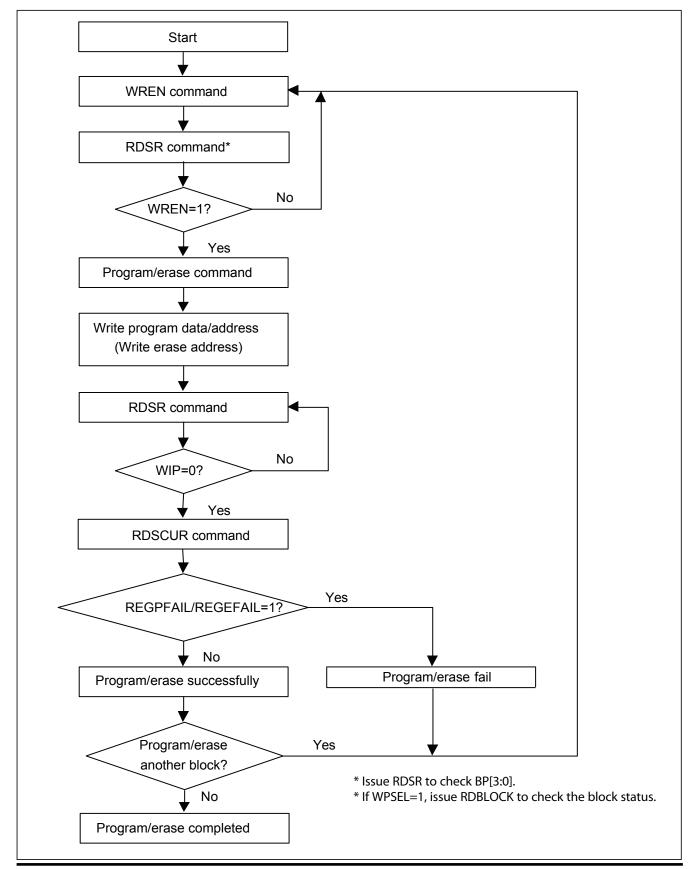




Figure 24. Program/Erase Flow(2) without read array data





10-20. Continuous Program mode (CP mode)

The CP mode may enhance program performance by automatically increasing address to the next higher address after each byte data has been programmed.

The Continuous Program (CP) instruction is for multiple bytes program to Flash. A write Enable (WREN) instruction must execute to set the Write Enable Latch (WEL) bit before sending the Continuous Program (CP) instruction. CS# requires to go high before CP instruction is executing. After CP instruction and address input, two bytes of data is input sequentially from MSB(bit7) to LSB(bit0). The first byte data will be programmed to the initial address range with A0=0 and second byte data with A0=1. If only one byte data is input, the CP mode will not process. If more than two bytes data are input, the additional data will be ignored and only two byte data are valid. Any byte to be programmed should be in the erase state (FF) first. It will not roll over during the CP mode, once the last unprotected address has been reached, the chip will exit CP mode and reset write Enable Latch bit (WEL) as "0" and CP mode bit as "0". Please check the WIP bit status if it is not in write progress before entering next valid instruction. During CP mode, the valid commands are CP command (AD hex), WRDI command (04 hex), RDSR command (05 hex), and RDSCUR command (2B hex). And the WRDI command is valid after completion of a CP programming cycle, which means the WIP bit=0.

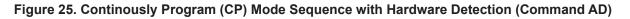
The sequence of issuing CP instruction is : CS# goes low \rightarrow sending CP instruction code \rightarrow 3-byte address on SI pin \rightarrow two data bytes on SI \rightarrow CS# goes high to low \rightarrow sending CP instruction and then continue two data bytes are programmed \rightarrow CS# goes high to low \rightarrow till last desired two data bytes are programmed \rightarrow CS# goes high to low \rightarrow till last desired two data bytes are programmed \rightarrow CS# goes high to low \rightarrow till last desired two data bytes are programmed \rightarrow CS# goes high to low \rightarrow sending WRDI (Write Disable) instruction to end CP mode \rightarrow send RDSR instruction to verify if CP mode word program ends, or send RDSCUR to check bit4 to verify if CP mode ends.

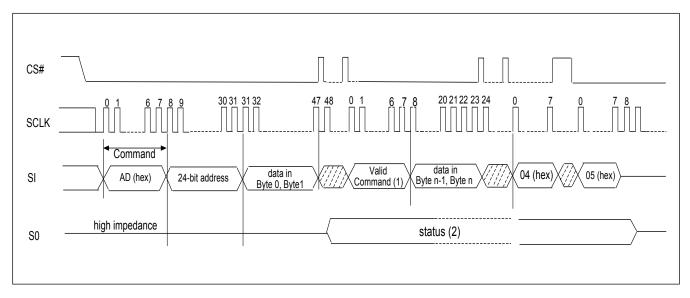
Three methods to detect the completion of a program cycle during CP mode:

- 1) Software method-I: by checking WIP bit of Status Register to detect the completion of CP mode.
- 2) Software method-II: by waiting for a tBP time out to determine if it may load next valid command or not.
- 3) Hardware method: by writing ESRY (enable SO to output RY/BY#) instruction to detect the completion of a program cycle during CP mode. The ESRY instruction must be executed before CP mode execution. Once it is enable in CP mode, the CS# goes low will drive out the RY/BY# status on SO, "0" indicates busy stage, "1" indicates ready stage, SO pin outputs tri-state if CS# goes high. DSRY (disable SO to output RY/BY#) instruction to disable the SO to output RY/BY# and return to status register data output during CP mode. Please note that the ESRY/DSRY commands are not accepted unless the completion of CP mode.

If the page is protected by BP3~0 (WPSEL=0) or by individual lock/permanent lock (WPSEL=1), the array data will be protected (no change) and the WEL bit will still be reset.







Notes:

- (1) During CP mode, the valid commands are CP command (AD hex), WRDI command (04 hex), RDSR command (05 hex), RDSCUR command (2B hex), RSTEN command (66 hex) and RST command (99hex).
- (2) Once an internal programming operation begins, CS# goes low will drive the status on the SO pin and CS# goes high will return the SO pin to tri-state.
- (3) To end the CP mode, either reaching the highest unprotected address or sending Write Disable (WRDI) command (04 hex) may achieve it and then it is recommended to send RDSR command (05 hex) to verify if CP mode is ended. Please be noticed that Software reset and Hardware reset can end the CP mode.



10-21. Deep Power-down (DP)

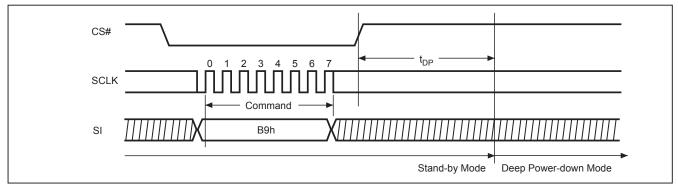
The Deep Power-down (DP) instruction is for setting the device on the minimizing the power consumption (to entering the Deep Power-down mode), the standby current is reduced from ISB1 to ISB2). The Deep Power-down mode requires the Deep Power-down (DP) instruction to enter, during the Deep Power-down mode, the device is not active and all Write/Program/Erase instructions are ignored. When CS# goes high, it's only in standby mode not deep power-down mode. It's different from Standby mode.

The sequence of issuing DP instruction is: CS# goes low \rightarrow sending DP instruction code \rightarrow CS# goes high.

The SIO[3:1] are don't care when during this mode.

Once the DP instruction is set, all instructions will be ignored except the Release from Deep Power-down mode (RDP) and Read Electronic Signature (RES) instruction. (those instructions allow the ID being reading out). When Power-down, the deep power-down mode automatically stops, and when power-up, the device automatically is in standby mode. For RDP instruction the CS# must go high exactly at the byte boundary (the latest eighth bit of instruction code has been latched-in); otherwise, the instruction will not be executed. As soon as Chip Select (CS#) goes high, a delay of tDP is required before entering the Deep Power-down mode and reducing the current to ISB2.







10-22. Release from Deep Power-down (RDP), Read Electronic Signature (RES)

The Release from Deep Power-down (RDP) instruction is terminated by driving Chip Select (CS#) High. When Chip Select (CS#) is driven High, the device is put in the standby Power mode. If the device was not previously in the Deep Power-down mode, the transition to the standby Power mode is immediate. If the device was previously in the Deep Power-down mode, though, the transition to the standby Power mode is delayed by tRES2, and Chip Select (CS#) must remain High for at least tRES2(max), as specified in *"12-4. AC CHARACTERISTICS"*. Once in the standby mode, the device waits to be selected, so that it can receive, decode and execute instructions.

RES instruction is for reading out the old style of 8-bit Electronic Signature, whose values are shown as "Table 7. ID Definitions". This is not the same as RDID instruction. It is not recommended to use for new design. For new design, please use RDID instruction. Even in Deep power-down mode, the RDP and RES are also allowed to be executed, only except the device is in progress of program/erase/write cycles; there's no effect on the current program/erase/write cycles in progress.

The SIO[3:1] are don't care when during this mode.

The RES instruction is ended by CS# goes high after the ID been read out at least once. The ID outputs repeatedly if continuously send the additional clock cycles on SCLK while CS# is at low. If the device was not previously in Deep Power-down mode, the device transition to standby mode is immediate. If the device was previously in Deep Power-down mode, there's a delay of tRES2 to transit to standby mode, and CS# must remain to high at least tRES2(max). Once in the standby mode, the device waits to be selected, so it can receive, decode, and execute instruction.

The RDP instruction is for releasing from Deep Power-down Mode.

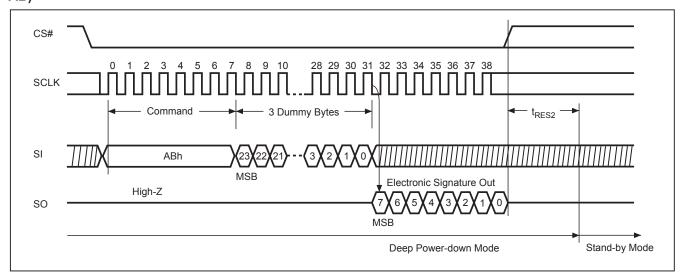
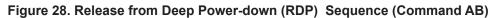
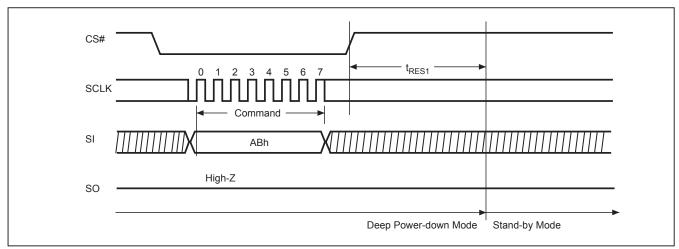


Figure 27. Release from Deep Power-down and Read Electronic Signature (RES) Sequence (Command AB)





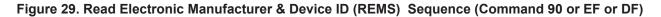


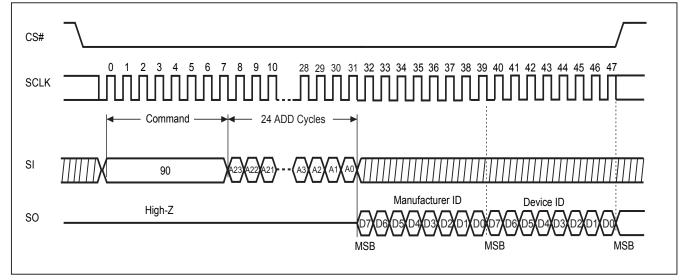


10-23. Read Electronic Manufacturer ID & Device ID (REMS), (REMS2), (REMS4)

The REMS, REMS2, and REMS4 instruction provides both the JEDEC assigned Manufacturer ID and the specific Device ID.

The instruction is initiated by driving the CS# pin low and shift the instruction code "90h", "DFh" or "EFh" followed by two dummy bytes and one byte address (A7~A0). After which, the Manufacturer ID for Macronix (C2h) and the Device ID are shifted out on the falling edge of SCLK with most significant bit (MSB) first as shown in the figure below. The Device ID values are listed in *"Table 7. ID Definitions"*. If the one-byte address is initially set to 01h, then the Device ID will be read first and then followed by the Manufacturer ID. The Manufacturer and Device IDs can be read continuously, alternating from one to the other. The instruction is completed by driving CS# high.





Notes:

- 1. A0=0 will output the Manufacturer ID first and A0=1 will output Device ID first. A1~A23 are don't care.
- 2. Instruction is either 90(hex) or EF(hex) or DF(hex).



10-24. ID Read

User can execute this ID Read instruction to identify the Device ID and Manufacturer ID. The sequence of issue ID instruction is CS# goes low—sending ID instruction—Data out on SO—CS# goes high. Most significant bit (MSB) first.

After the command cycle, the device will immediately output data on the falling edge of SCLK. The manufacturer ID, memory type, and device ID data byte will be output continuously, until the CS# goes high.

Command Type	MX25L3255E							
RDID	manufacturer ID	memory type	memory density					
טוטא	C2	C2 9E						
RES	electronic ID							
RES	9E							
REMS/REMS2/	manufacturer ID							
REMS4	C2	9E						

Table 7. ID Definitions

10-25. Enter Secured OTP (ENSO)

The ENSO instruction is for entering the additional 4K-bit Secured OTP mode. The additional 4K-bit Secured OTP is independent from main array, which may use to store unique serial number for system identifier. After entering the Secured OTP mode, and then follow standard read or program procedure to read out the data or update data. The Secured OTP data cannot be updated again once it is lock-down.

The sequence of issuing ENSO instruction is: CS# goes low \rightarrow sending ENSO instruction to enter Secured OTP mode \rightarrow CS# goes high.

The SIO[3:1] are don't care when during this mode.

Please note that WRSR/WRSCUR/WPSEL/SBLK/GBLK/SBULK/GBULK/CE/BE/SE/BE32K commands are not acceptable during the access of secure OTP region, once Security OTP is locked down, only read related commands are valid.

10-26. Exit Secured OTP (EXSO)

The EXSO instruction is for exiting the additional 4K-bit Secured OTP mode. The sequence of issuing EXSO instruction is: CS# goes low \rightarrow sending EXSO instruction to exit Secured OTP mode \rightarrow CS# goes high.

The SIO[3:1] are don't care when during this mode.



10-27. Read Security Register (RDSCUR)

The RDSCUR instruction is for reading the value of Security Register. The Read Security Register can be read at any time (even in program/erase/write status register/write security register condition) and continuously.

The sequence of issuing RDSCUR instruction is : CS# goes low \rightarrow sending RDSCUR instruction \rightarrow Security Register data out on SO \rightarrow CS# goes high.

The SIO[3:1] are don't care when during this mode.

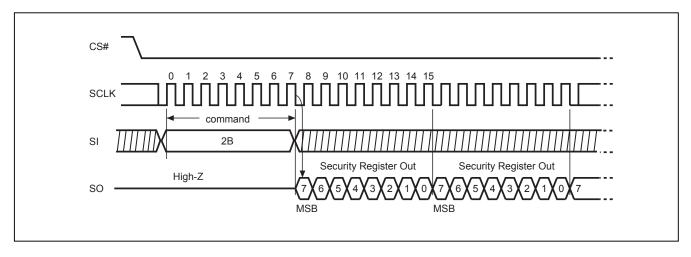


Figure 30. Read Security Register (RDSCUR) Sequence (Command 2B)

The definition of the Security Register is as below:

Secured OTP Indicator bit. The Secured OTP indicator bit shows the chip is locked by factory before ex- factory or not. When it is "0", it indicates non-factory lock; "1" indicates factory- lock.

Lock-down Secured OTP (LDSO) bit. By writing WRSCUR instruction, the LDSO bit may be set to "1" for customer lock-down purpose. However, once the bit is set to "1" (lock-down), the LDSO bit and the 4K-bit Secured OTP area cannot be updated any more. While it is in 4K-bit Secured OTP mode, array access is not allowed.

Continuous Program Mode (CP mode) bit. The Continuous Program Mode bit indicates the status of CP mode, "0" indicates not in CP mode; "1" indicates in CP mode.

Program Fail Flag bit. While a program failure happened, the Program Fail Flag bit would be set. If the program operation fails on a protected memory region or locked OTP region, this bit will also be set. This bit can be the failure indication of one or more program operations. This fail flag bit will be cleared automatically after the next successful program operation.

Erase Fail Flag bit. While an erase failure happened, the Erase Fail Flag bit would be set. If the erase operation fails on a protected memory region or locked OTP region, this bit will also be set. This bit can be the failure indication of one or more erase operations. This fail flag bit will be cleared automatically after the next successful erase operation.



Write Protection Select bit. The Write Protection Select bit indicates that WPSEL has been executed successfully. Once this bit has been set (WPSEL=1), all the blocks or sectors will be write-protected after the poweron every time. Once WPSEL has been set, it cannot be changed again, which means it's only for individual WP mode.

Under the individual block protection mode (WPSEL=1), hardware protection is performed by driving WP#=0. Once WP#=0, all array blocks/sectors are protected regardless of the contents of SRAM lock bits.

bit7	bit6	bit5	bit4	bit3	bit2	bit1	bit0
WPSEL	E_FAIL	P_FAIL	Continuously Program mode (CP mode)	Reserved	Reserved	LDSO (lock-down 4K-bit Se- cured OTP)	4K-bit Secured OTP
0=normal WP mode 1=individual WP mode (default=0)	0=normal Erase succeed 1=indicate Erase failed (default=0)	0=normal Program succeed 1=indicate Program failed (default=0)	0=normal Program mode 1=CP mode (default=0)	_	-	0 = not lockdown 1 = lock- down (cannot program/ erase OTP)	0 = nonfactory lock 1 = factory lock
non-volatile bit	volatile bit	volatile bit	volatile bit	volatile bit	volatile bit	non-volatile bit	non-volatile bit
OTP	Read Only	Read Only	Read Only	Read Only	Read Only	OTP	Read Only

Table 8. Security Register Definition



10-28. Write Security Register (WRSCUR)

The WRSCUR instruction is for changing the values of Security Register Bits. The WREN instruction is required before sending WRSCUR instruction. The WRSCUR instruction may change the values of bit1 (LDSO bit) for customer to lock-down the 4K-bit Secured OTP area. Once the LDSO bit is set to "1", the Secured OTP area cannot be updated any more.

The sequence of issuing WRSCUR instruction is :CS# goes low \rightarrow sending WRSCUR instruction \rightarrow CS# goes high.

The SIO[3:1] are don't care when during this mode.

The CS# must go high exactly at the boundary; otherwise, the instruction will be rejected and not executed.

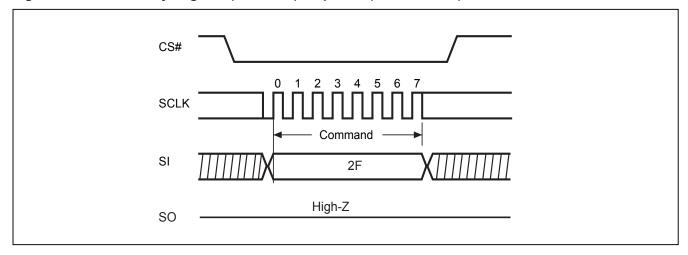


Figure 31. Write Security Register (WRSCUR) Sequence (Command 2F)

10-29. Write Protection Selection (WPSEL)

There are two write protection methods, (1) BP protection mode (2) individual block protection mode. If WPSEL=0, flash is under BP protection mode. If WPSEL=1, flash is under individual block protection mode. The default value of WPSEL is "0". WPSEL command can be used to set WPSEL=1. **Please note that WPSEL is an OTP bit. Once WPSEL is set to 1, there is no chance to recovery WPSEL back to "0".** If the flash is put on BP mode, the individual block protection mode is disabled. Contrarily, if flash is on the individual block protection mode, the BP mode is disabled.

The SIO[3:1] are don't care when during this mode.

Every time after the system is powered-on, and the Security Register bit 7 is checked to be WPSEL=1, all the blocks or sectors will be write protected by default. User may only unlock the blocks or sectors via SBULK and GBULK instruction. Program or erase functions can only be operated after the Unlock instruction is conducted.

BP protection mode, WPSEL=0:

ARRAY is protected by BP3~BP0 and BP3~BP0 bits are protected by "SRWD=1 and WP#=0", where SRWD is bit 7 of status register that can be set by WRSR command.



Individual block protection mode, WPSEL=1:

Blocks are individually protected by their own SRAM lock bits which are set to "1" after power up. SBULK and SBLK command can set SRAM lock bit to "0" and "1". When the system accepts and executes WPSEL instruction, the bit 7 in security register will be set. It will activate SBLK, SBULK, RDBLOCK, GBLK, GBULK, PLOCK, RDPLOCK, PLLK, RDPLLK, WRLCR, RRLCR, etc instructions to conduct block lock protection and replace the original Software Protect Mode (SPM) use (BP3~BP0) indicated block methods. Under the individual block protection mode (WPSEL=1), hardware protection is performed by driving WP#=0. Once WP#=0, all array blocks/ sectors are protected regardless of the contents of SRAM lock bits.

The WREN (Write Enable) instruction is required before issuing WPSEL instruction.

The sequence of issuing WPSEL instruction is: CS# goes low \rightarrow sending WPSEL instruction to enter the individual block protect mode \rightarrow CS# goes high.

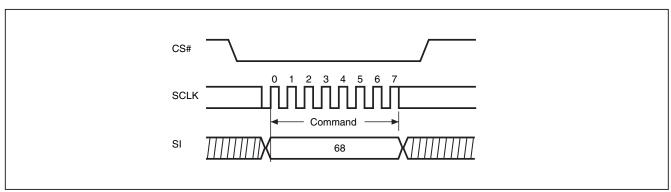
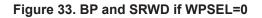


Figure 32. Write Protection Selection (WPSEL) Sequence (Command 68)

WPSEL instruction function flow is as follows:



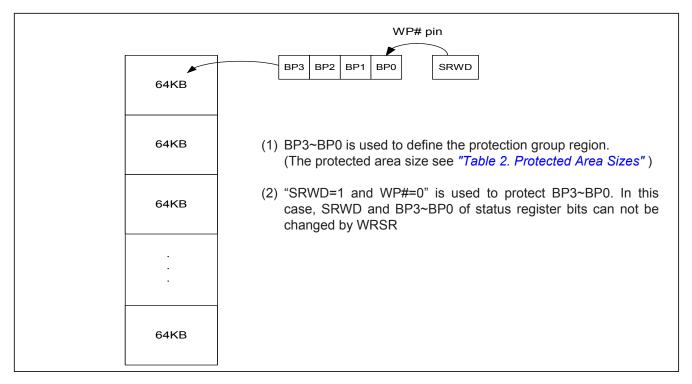




Figure 34. The individual block lock mode is effective after setting WPSEL=1

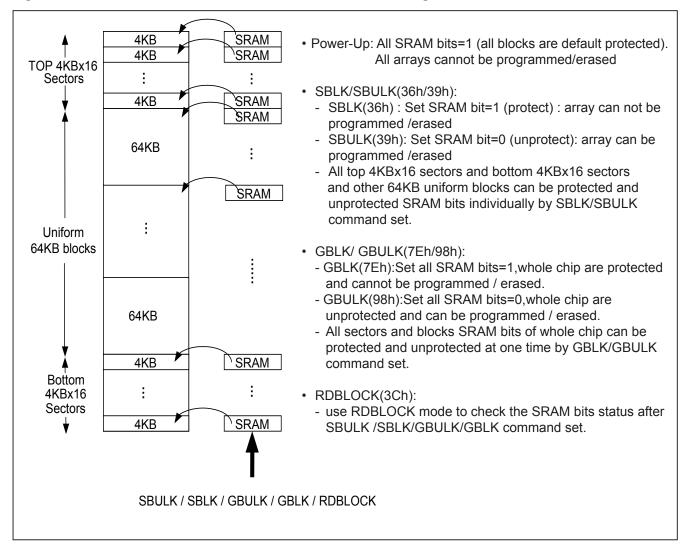
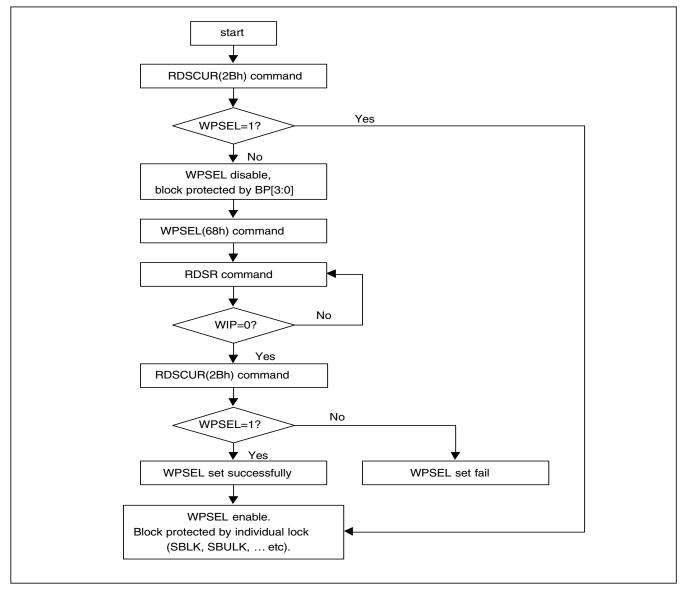




Figure 35. WPSEL Flow





10-30. Single Block Lock/Unlock Protection (SBLK/SBULK)

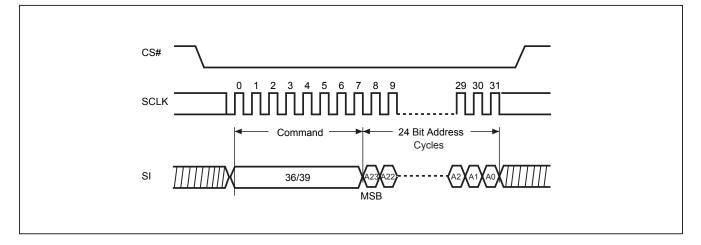
These instructions are only effective after WPSEL was executed. The SBLK instruction is for write protection a specified block(or sector) of memory, using A23-A16 or (A23-A12) address bits to assign a 64Kbytes block (or 4K bytes sector) to be protected as read only. The SBULK instruction will cancel the block (or sector) write protection state. This feature allows user to stop protecting the entire block (or sector) through the chip unprotect command (GBULK).

The WREN (Write Enable) instruction is required before issuing SBLK/SBULK instruction. The sequence of issuing SBLK/SBULK instruction is: CS# goes low \rightarrow send SBLK/SBULK (36h/39h) instruction \rightarrow send 3 address bytes assign one block (or sector) to be protected on SI pin \rightarrow CS# goes high.

The CS# must go high exactly at the byte boundary, otherwise the instruction will be rejected and not be executed.

The SIO[3:1] are don't care when during this mode.







SBLK/SBULK instruction function flow is as follows:

Figure 37. Block Lock Flow

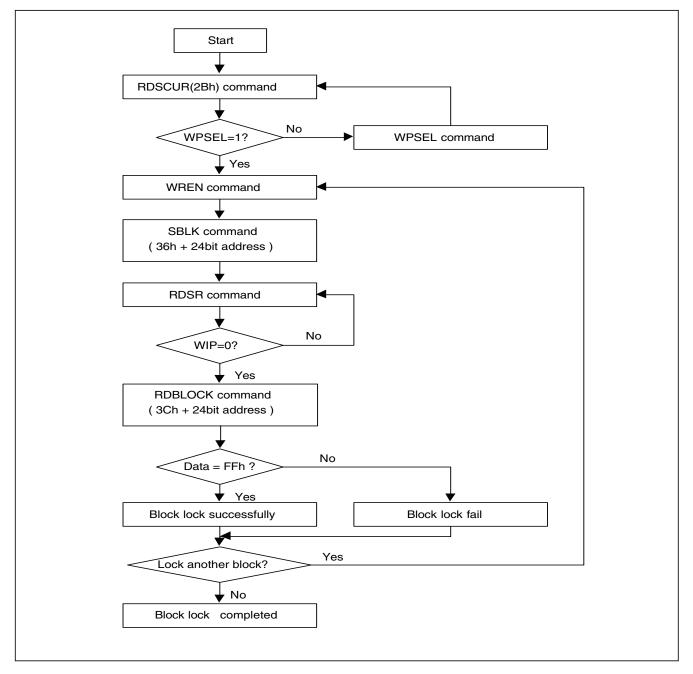
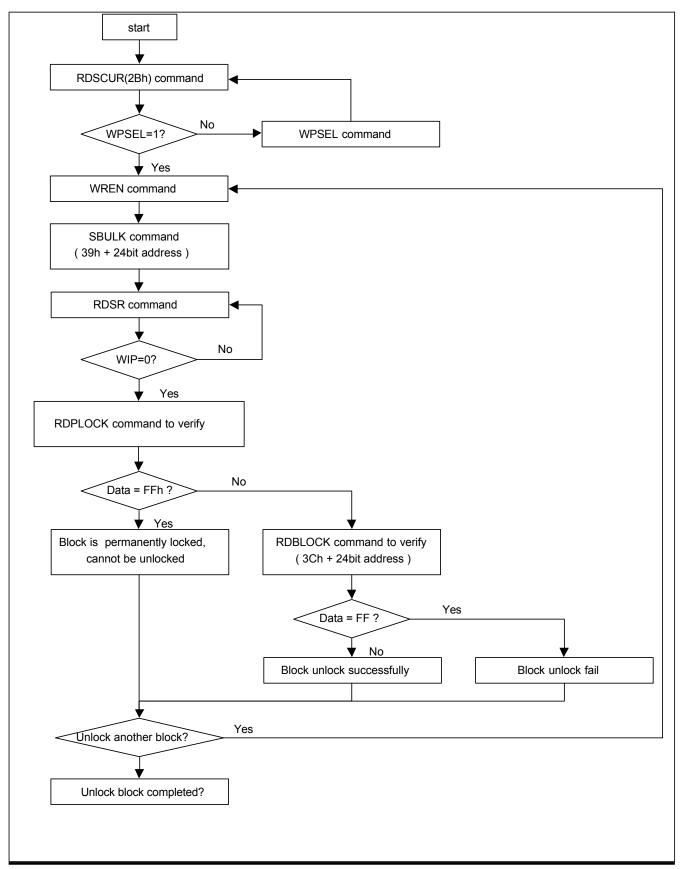




Figure 38. Block Unlock Flow



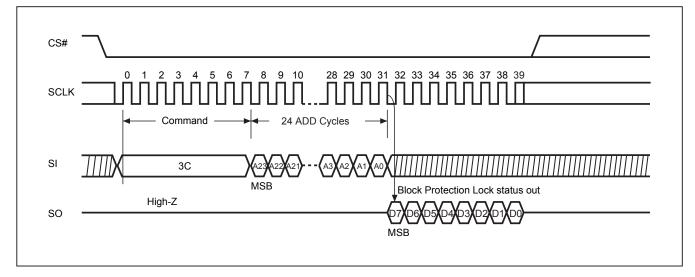


10-31. Read Block Lock Status (RDBLOCK)

This instruction is only effective after WPSEL was executed. The RDBLOCK instruction is for reading the status of protection lock of a specified block(or sector), using A23-A16 (or A23-A12) address bits to assign a 64K bytes block (4K bytes sector) and read protection lock status bit which the first byte of Read-out cycle. The status bit is"1" to indicate that this block has been protected, that user can read only but cannot write/program /erase this block. The status bit is "0" to indicate that this block hasn't be protected, and user can read and write this block.

The sequence of issuing RDBLOCK instruction is: CS# goes low \rightarrow send RDBLOCK (3Ch) instruction \rightarrow send 3 address bytes to assign one block on SI pin \rightarrow read block's protection lock status bit on SO pin \rightarrow CS# goes high.

The SIO[3:1] are don't care when during this mode.







10-32. Gang Block Lock/Unlock (GBLK/GBULK)

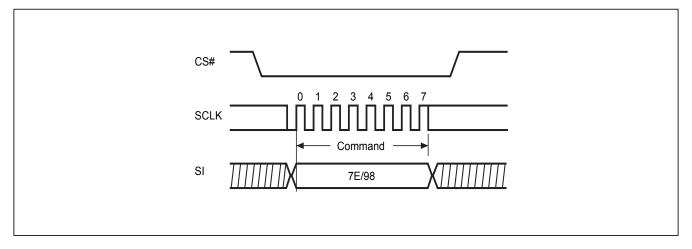
These instructions are only effective after WPSEL was executed. The GBLK/GBULK instruction is for enable/disable the lock protection block of the whole chip.

The WREN (Write Enable) instruction is required before issuing GBLK/GBULK instruction. The sequence of issuing GBLK/GBULK instruction is: CS# goes low \rightarrow send GBLK/GBULK (7Eh/98h) instruction \rightarrow CS# goes high.

The CS# must go high exactly at the byte boundary, otherwise, the instruction will be rejected and not be executed.

The SIO[3:1] are don't care when during this mode.





10-33. Enable SO to Output RY/BY# (ESRY)

The ESRY instruction is for outputting the ready/busy status to SO during CP mode.

The sequence of issuing ESRY instruction is: CS# goes low \rightarrow sending ESRY instruction code \rightarrow CS# goes high.

The CS# must go high exactly at the byte boundary; otherwise, the instruction will be rejected and not executed.

10-34. Disable SO to Output RY/BY# (DSRY)

The DSRY instruction is for resetting ESRY during CP mode. The ready/busy status will not output to SO after DSRY issued.

The sequence of issuing DSRY instruction is: CS# goes low \rightarrow send DSRY instruction code \rightarrow CS# goes high. The CS# must go high exactly at the byte boundary; otherwise, the instruction will be rejected and not executed.



10-35. No Operation (NOP)

The "No Operation" command is only able to terminate the Reset Enable (RSTEN) command and will not affect any other command.

The SIO[3:1] are don't care when during this mode.

10-36. Software Reset (Reset-Enable (RSTEN) and Reset (RST))

The Software Reset operation combines two instructions: Reset-Enable (RSTEN) command and Reset (RST) command. It returns the device to standby mode.

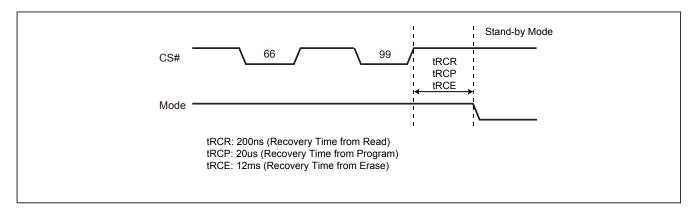
To execute Reset command (RST), the Reset-Enable (RSTEN) command must be executed first to perform the Reset operation. If there is any other command to interrupt after the Reset-Enable command, the Reset-Enable will be invalid.

The SIO[3:1] are don't care when during this mode.

If the Reset command is executed during program or erase operation, the operation will be disabled, the data under processing could be damaged or lost.

The reset time is different depending on the last operation. Longer latency time is required to recover from a program operation than from other operations.

Figure 41. Software Reset Recovery





10-37. Read SFDP Mode (RDSFDP)

The Serial Flash Discoverable Parameter (SFDP) standard provides a consistent method of describing the functional and feature capabilities of serial flash devices in a standard set of internal parameter tables. These parameter tables can be interrogated by host system software to enable adjustments needed to accommodate divergent features from multiple vendors. The concept is similar to the one found in the Introduction of JEDEC Standard, JESD68 on CFI.

The sequence of issuing RDSFDP instruction is same as CS# goes low \rightarrow send RDSFDP instruction (5Ah) \rightarrow send 3 address bytes on SI pin \rightarrow send 1 dummy byte on SI pin \rightarrow read SFDP code on SO \rightarrow to end RDSFDP operation can use CS# to high at any time during data out.

SFDP is a JEDEC Standard, JESD216.

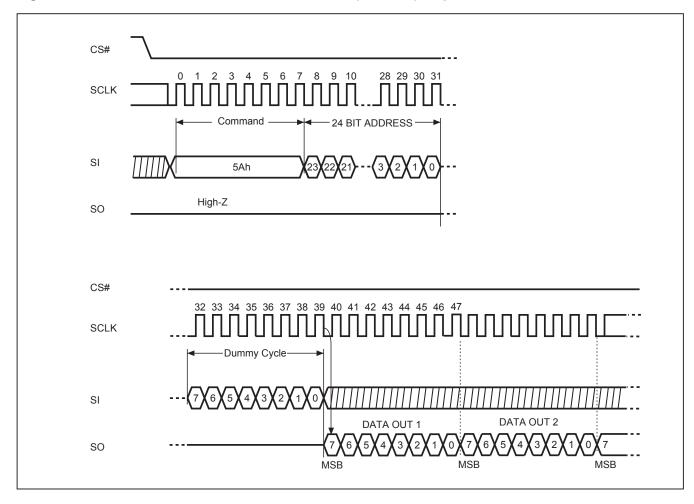


Figure 42. Read Serial Flash Discoverable Parameter (RDSFDP) Sequence



MX25L3255E

Table 9. Signature and Parameter Identification Data Values

Description	Description Comment		DW Add (Bit)	Data (h/b) (Note1)	Data (h)
		00h	07:00	53h	53h
		01h	15:08	46h	46h
SFDP Signature	Fixed: 50444653h	02h	23:16	44h	44h
		03h	31:24	50h	50h
SFDP Minor Revision Number	Start from 00h	04h	07:00	00h	00h
SFDP Major Revision Number	Start from 01h	05h	15:08	01h	01h
Number of Parameter Headers	This number is 0-based. Therefore, 0 indicates 1 parameter header.	06h	23:16	01h	01h
Unused		07h	31:24	FFh	FFh
ID number (JEDEC)	00h: it indicates a JEDEC specified header.	08h	07:00	00h	00h
Parameter Table Minor Revision Number	Start from 00h	09h	15:08	00h	00h
Parameter Table Major Revision Number	Start from 01h	0Ah	23:16	01h	01h
Parameter Table Length (in double word)	How many DWORDs in the Parameter table	0Bh	31:24	09h	09h
		0Ch	07:00	30h	30h
	First address of JEDEC Flash	0Dh	15:08	00h	00h
Parameter Table Pointer (PTP)	Parameter table	0Eh	23:16	00h	00h
Unused		0Fh	31:24	FFh	FFh
ID number (Macronix manufacturer ID)	it indicates Macronix manufacturer ID	10h	07:00	C2h	C2h
Parameter Table Minor Revision Number	Start from 00h	11h	15:08	00h	00h
Parameter Table Major Revision Number	Start from 01h	12h	23:16	01h	01h
Parameter Table Length (in double word)	How many DWORDs in the Parameter table	13h	31:24	04h	04h
		14h	07:00	60h	60h
Parameter Table Pointer (PTP)	First address of Macronix Flash Parameter table	15h	15:08	00h	00h
		16h	23:16	00h	00h
Unused		17h	31:24	FFh	FFh



Table 10. Parameter Table (0): JEDEC Flash Parameter Tables

Description			DW Add (Bit)	Data (h/b) (Note1)	Data (h)	
Block/Sector Erase sizes	00: Reserved, 01: 4KB erase, 10: Reserved, 11: not suport 4KB erase		01:00	01b	_	
Write Granularity	0: 1Byte, 1: 64Byte or larger		02	1b		
Write Enable Instruction Required for Writing to Volatile Status Registers	0: not required 1: required 00h to be written to the status register	30h	03	0b	E5h	
Write Enable Opcode Select for Writing to Volatile Status Registers	0: use 50h opcode, 1: use 06h opcode Note: If target flash status register is nonvolatile, then bits 3 and 4 must be set to 00b.		04	0b		
Unused	Contains 111b and can never be changed		07:05	111b		
4KB Erase Opcode		31h	15:08	20h	20h	
(1-1-2) Fast Read (Note2)	0=not support 1=support		16	1b		
Address Bytes Number used in addressing flash array	00: 3Byte only, 01: 3 or 4Byte, 10: 4Byte only, 11: Reserved		18:17	00b	F1h	
Double Transfer Rate (DTR) Clocking	0=not support 1=support		19	0b		
(1-2-2) Fast Read	0=not support 1=support	32h	20	1b		
(1-4-4) Fast Read	0=not support 1=support		21	1b		
(1-1-4) Fast Read	0=not support 1=support		22	1b		
Unused			23	1b		
Unused		33h	31:24	FFh	FFh	
Flash Memory Density		37h:34h	31:00	01FF FF	FFh	
(1-4-4) Fast Read Number of Wait states (Note3)	0 0000b: Wait states (Dummy Clocks) not support	- 38h	04:00	0 0100b	44h	
(1-4-4) Fast Read Number of Mode Bits (Note4)	000b: Mode Bits not support	3011	07:05	010b	4411	
(1-4-4) Fast Read Opcode		39h	15:08	EBh	EBh	
(1-1-4) Fast Read Number of Wait states	Wait 0 0000b: Wait states (Dummy Clocks) not support		20:16	0 1000b	08h	
(1-1-4) Fast Read Number of Mode Bits	000b: Mode Bits not support	3Ah	23:21	000b		
(1-1-4) Fast Read Opcode		3Bh	31:24	6Bh	6Bh	



Description	Comment	Add (h) (Byte)	DW Add (Bit)	Data (h/b) (Note1)	Data (h)	
(1-1-2) Fast Read Number of Wait states	0 0000b: Wait states (Dummy Clocks) not support	3Ch	04:00	0 1000b	08h	
(1-1-2) Fast Read Number of Mode Bits	000b: Mode Bits not support	3011	07:05	000b	0011	
(1-1-2) Fast Read Opcode		3Dh	15:08	3Bh	3Bh	
(1-2-2) Fast Read Number of Wait states	0 0000b: Wait states (Dummy Clocks) not support	3Eh	20:16	0 0100b	04h	
(1-2-2) Fast Read Number of Mode Bits	000b: Mode Bits not support	5211	23:21	000b	0411	
(1-2-2) Fast Read Opcode		3Fh	31:24	BBh	BBh	
(2-2-2) Fast Read	0=not support 1=support		00	0b		
Unused		406	03:01	111b	ГГЬ	
(4-4-4) Fast Read	0=not support 1=support	40h	04	0b	EEh	
Unused			07:05	111b		
Unused		43h:41h	31:08	FFh	FFh	
Unused		45h:44h	15:00	FFh	FFh	
(2-2-2) Fast Read Number of Wait states	0 0000b: Wait states (Dummy Clocks) not support	46h	20:16	0 0000b	00h	
(2-2-2) Fast Read Number of Mode Bits	000b: Mode Bits not support	4011	23:21	000b		
(2-2-2) Fast Read Opcode		47h	31:24	FFh	FFh	
Unused		49h:48h	15:00	FFh	FFh	
(4-4-4) Fast Read Number of Wait states	0 0000b: Wait states (Dummy Clocks) not support	4Ah	20:16	0 0000b	00h	
(4-4-4) Fast Read Number of Mode Bits	000b: Mode Bits not support		23:21	000b	0011	
(4-4-4) Fast Read Opcode		4Bh	31:24	FFh	FFh	
Sector Type 1 Size	Sector/block size = 2 ^N bytes (Note5) 0x00b: this sector type doesn't exist	4Ch	07:00	0Ch	0Ch	
Sector Type 1 erase Opcode		4Dh	15:08	20h	20h	
Sector Type 2 Size	Sector/block size = 2 ^N bytes 0x00b: this sector type doesn't exist	4Eh	23:16	0Fh	0Fh	
Sector Type 2 erase Opcode		4Fh	31:24	52h	52h	
Sector Type 3 Size	Sector/block size = 2^N bytes 0x00b: this sector type doesn't exist	50h	07:00	10h	10h	
Sector Type 3 erase Opcode		51h	15:08	D8h	D8h	
Sector Type 4 Size	Sector/block size = 2^N bytes 0x00b: this sector type doesn't exist	52h	23:16	00h	00h	
Sector Type 4 erase Opcode		53h	31:24	FFh	FFh	



Table 11. Parameter Table (1): Macronix Flash Parameter Tables

Description	Comment	Add (h) (Byte)	DW Add (Bit)	Data (h/b) (Note1)	Data (h)
Vcc Supply Maximum Voltage	2000h=2.000V 2700h=2.700V 3600h=3.600V	61h:60h	07:00 15:08	00h 36h	00h 36h
Vcc Supply Minimum Voltage	1650h=1.650V 2250h=2.250V 2350h=2.350V 2700h=2.700V	63h:62h	23:16 31:24	00h 27h	00h 27h
H/W Reset# pin	0=not support 1=support		00	0b	
H/W Hold# pin	0=not support 1=support		01	1b	
Deep Power Down Mode	0=not support 1=support		02	1b	
S/W Reset	0=not support 1=support		03	1b	
S/W Reset Opcode	Reset Enable (66h) should be issued before Reset Opcode	65h:64h	11:04	1001 1001b (99h)	499Eh
Program Suspend/Resume	e 0=not support 1=support		12	0b	
Erase Suspend/Resume	0=not support 1=support		13	0b	
Unused			14	1b	
Wrap-Around Read mode	0=not support 1=support		15	0b	
Wrap-Around Read mode Opcode		66h	23:16	FFh	FFh
Wrap-Around Read data length	08h:support 8B wrap-around read 16h:8B&16B 32h:8B&16B&32B 64h:8B&16B&32B&64B	67h	31:24	FFh	FFh
Individual block lock	0=not support 1=support		00	1b	
Individual block lock bit (Volatile/Nonvolatile)	0=Volatile 1=Nonvolatile		01	0b	
Individual block lock Opcode			09:02	0011 0110b (36h)	
Individual block lock Volatile protect bit default protect status	0=protect 1=unprotect	CDb.Cob	10	0b	F8D9h
Secured OTP	0=not support 1=support	6Bh:68h	11	1b	
Read Lock	0=not support 1=support		12	1b	
Permanent Lock	0=not support 1=support		13	1b	
Unused			15:14	11b	
Unused			31:16	FFh	FFh
Unused		6Fh:6Ch	31:00	FFh	FFh





Note 1: h/b is hexadecimal or binary.

- Note 2: **(x-y-z)** means I/O mode nomenclature used to indicate the number of active pins used for the opcode (x), address (y), and data (z). At the present time, the only valid Read SFDP instruction modes are: (1-1-1), (2-2-2), and (4-4-4)
- Note 3: Wait States is required dummy clock cycles after the address bits or optional mode bits.
- Note 4: **Mode Bits** is optional control bits that follow the address bits. These bits are driven by the system controller if they are specified. (eg,read performance enhance toggling bits)
- Note 5: 4KB=2^0Ch,32KB=2^0Fh,64KB=2^10h
- Note 6: All unused and undefined area data is blank FFh.



11. POWER-ON STATE

The device is at below states when power-up:

- Standby mode (please note it is not Deep Power-down mode)
- Write Enable Latch (WEL) bit is reset

The device must not be selected during power-up and power-down stage unless the VCC achieves below correct level:

- VCC minimum at power-up stage and then after a delay of tVSL
- GND at power-down

Please note that a pull-up resistor on CS# may ensure a safe and proper power-up/down level.

An internal Power-on Reset (POR) circuit may protect the device from data corruption and inadvertent data change during power up state.

For further protection on the device, if the VCC does not reach the VCC minimum level, the correct operation is not guaranteed. The read, write, erase, and program command should be sent after the time delay:

tVSL after VCC reached VCC minimum level

The device can accept read command after VCC reached VCC minimum and a time delay of tVSL.

Note:

- To stabilize the VCC level, the VCC rail decoupled by a suitable capacitor close to package pins is recommended. (generally around 0.1uF)



MX25L3255E

12. ELECTRICAL SPECIFICATIONS

12-1. ABSOLUTE MAXIMUM RATINGS

RATING	VALUE
Ambient Operating Temperature	-40°C to 85°C
Storage Temperature	-65°C to 150°C
Applied Input Voltage	-0.5V to 4.6V
Applied Output Voltage	-0.5V to 4.6V
VCC to Ground Potential	-0.5V to 4.6V

NOTICE:

1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is stress rating only and functional operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended period may affect reliability.

- 2. Specifications contained within the following tables are subject to change.
- 3. During voltage transitions, all pins may overshoot Vss to -2.0V and Vcc to +2.0V for periods up to 20ns, see the figures below.

Figure 43. Maximum Negative Overshoot Waveform

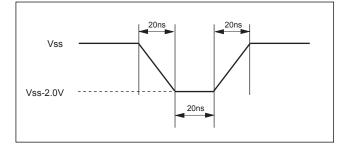
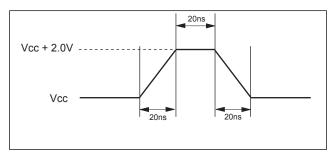


Figure 44. Maximum Positive Overshoot Waveform



12-2. CAPACITANCE

TA = 25°C, f = 1.0 MHz

Symbo	Parameter	Min.	Тур.	Max.	Unit	Conditions
CIN	Input Capacitance			20	pF	VIN = 0V
COUT	Output Capacitance			20	pF	VOUT = 0V



Figure 45. INPUT TEST WAVEFORMS AND MEASUREMENT LEVEL

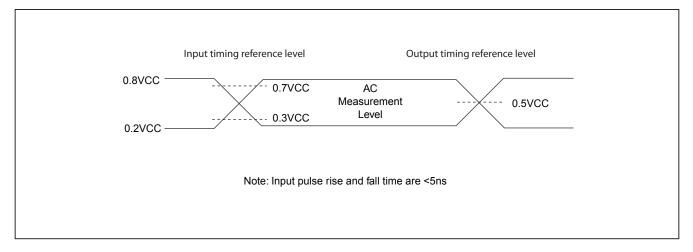
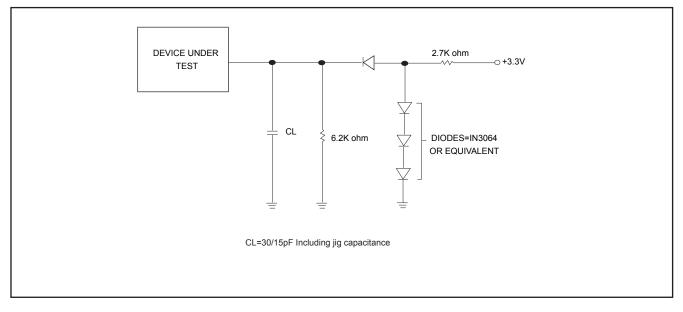


Figure 46. OUTPUT LOADING





MX25L3255E

12-3. DC CHARACTERISTICS

Temperature = -40°C to 85°C for Industrial grade

Symbol	Parameter	Notes	Min.	Max.	Units	Test Conditions
ILI	Input Load Current	1		± 2	uA	VCC = VCC Max, VIN = VCC or GND
ILO	Output Leakage Current	1		± 2	uA	VCC = VCC Max, VOUT = VCC or GND
ISB1	VCC Standby Current	1		80	uA	VIN = VCC or GND, CS# = VCC
ISB2	Deep Power-down Current		5	40	uA	VIN = VCC or GND, CS# = VCC
				35	mA	f=104MHz (4 x I/O read) SCLK=0.1VCC/0.9VCC, SO=Open
				19	mA	f=104MHz (1 x I/O read) SCLK=0.1VCC/0.9VCC, SO=Open
ICC1	VCC Read	1		25	mA	fQ=86MHz (4 x I/O read) SCLK=0.1VCC/0.9VCC, SO=Open
				20	mA	fT=86MHz (2 x I/O read) SCLK=0.1VCC/0.9VCC, SO=Open
				10	mA	f=33MHz, SCLK=0.1VCC/0.9VCC, SO=Open
ICC2	VCC Program Current (PP)	1		25	mA	Program in Progress, CS# = VCC
ICC3	VCC Write Status Register (WRSR) Current			20	mA	Program status register in progress, CS#=VCC
ICC4	VCC Sector Erase Current (SE)	1		25	mA	Erase in Progress, CS#=VCC
ICC5	VCC Chip Erase Current (CE)	1		25	mA	Erase in Progress, CS#=VCC
VIL	Input Low Voltage		-0.5	0.8	V	
VIH	Input High Voltage		0.7VCC	VCC+0.4	V	
VOL	Output Low Voltage			0.4	V	IOL = 1.6mA
VOH	Output High Voltage		VCC-0.2		V	IOH = -100uA

Notes :

1. Typical values at VCC = 3.3V, T = 25°C. These currents are valid for all product versions (package and speeds).

2. Typical value is calculated by simulation.

3. The value guaranteed by characterization, not 100% tested in production.



12-4. AC CHARACTERISTICS

Temperature = -40°C to 85°C for Industrial grade

Symbol	Alt.	Parameter			Min.	Тур.	Max.	Unit	
fSCLK	fC	Clock Frequency for the fo FAST_READ, RDSFDP, P WREN, WRDI, RDID, RDS	D.C.		104	MHz			
fRSCLK	fR	Clock Frequency for READ	Clock Frequency for READ instructions						
fTSCLK	fT	Clock Frequency for 2REA			86	MHz			
HOULK	fQ	Clock Frequency for 4REA	Clock Frequency for 4READ/QREAD instructions (4)					MHz	
f4PP		Clock Frequency for 4PP (Quad page	e program)			86	MHz	
tCH(1)		Clock High Time	4.5			ns			
			Normal Read (TRSULK)					ns	
tCL(1)	tCLL	Clock Low Time	ck Low Time Others (fSCLK)					ns	
			Normal Read (fRSCLK					ns	
tCLCH		Clock Rise Time (3) (peak	. /		0.1			V/ns	
tCHCL		Clock Fall Time (3) (peak t			0.1			V/ns	
tSLCH	tCSS	CS# Active Setup Time (re		,	3			ns	
tCHSL		CS# Not Active Hold Time	(relative to	SCLK)	3			ns	
tDVCH	tDSU	Data In Setup Time	2			ns			
tCHDX	tDH	Data In Hold Time	2			ns			
tCHSH		CS# Active Hold Time (rela	3			ns			
tSHCH		CS# Not Active Setup Time	3			ns			
tSHSL(3)	HO SH	CS# Deselect Time	Read	15			ns		
131132(3)		CS# Deselect Time		Write/Erase/Program	50			ns	
tSHQZ		Output Disable Time		2.7V-3.6V			10	ns	
ISHQZ	tDIS	Output Disable Time		3.0V-3.6V			8	ns	
tHLCH		HOLD# Active Setup Time	(relative to	SCLK)	5			ns	
tCHHH		HOLD# Active Hold Time (relative to	SCLK)	5			ns	
tHHCH		HOLD# Not Active Setup T	ime (relati	ve to SCLK)	5			ns	
tCHHL		HOLD# Hold Time (relative	e to SCLK)		5			ns	
	47	HOLD# to Output Low-Z		2.7V-3.6V		İ	10	ns	
tHHQX	tLZ	Loading=30pF		3.0V-3.6V		İ	8	ns	
411.07	417	HOLD# to Output High-Z		2.7V-3.6V			10	ns	
tHLQZ	tHZ	Loading=30pF		3.0V-3.6V			8	ns	
			Loading:	1 I/O		İ	5	ns	
			10pF	2 1/0 & 4 1/0			6	ns	
tCLQV	tV	Clock Low to Output Valid	Loading:	1 I/O			6	ns	
ICLQV		VCC=2.7V~3.6V	15pF	2 1/0 & 4 1/0			6	ns	
			Loading:				7	ns	
				2 1/0 & 4 1/0			8	ns	
tCLQX	tHO	Output Hold Time			1			ns	
tWHSL		Write Protect Setup Time			20			ns	
tSHWL		Write Protect Hold Time			100			ns	
tDP		CS# High to Deep Power-	down Mode	9			10	us	
tRES1		CS# High to Standby M Read					100	us	
tRES2		CS# High to Standby Mode	e with Elec	tronic Signature Read			100	us	



Symbol	Alt.	Parameter	Min.	Тур.	Max.	Unit
tW		Write Status Register Cycle Time			40	ms
tBP		Byte-Program		12	300	us
tPP		Page Program Cycle Time		1.4	5	ms
tSE		Sector Erase Cycle Time (4KB)		60	300	ms
tBE		Block Erase Cycle Time (32KB)		0.5	2	S
tBE		Block Erase Cycle Time (64KB)		0.7	2	S
tCE		Chip Erase Cycle Time		25	50	S
tWPS		Write Protection Selection Time			1	ms
tWSR		Write Security Register Time			1	ms

Notes:

- tCH + tCL must be greater than or equal to 1/ fC.
 The value guaranteed by characterization, not 100% tested in production.
- Only applicable as a constraint for a WRSR instruction when SRWD is set at 1.
 For 4READ instruction, when dummy cycle=6, clock rate is 86MHz, and when dummy cycle=8, clock rate is 104MHz.



13. TIMING ANALYSIS

Figure 47. Serial Input Timing

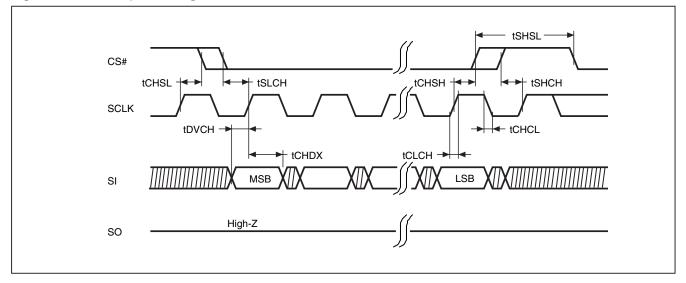


Figure 48. Output Timing

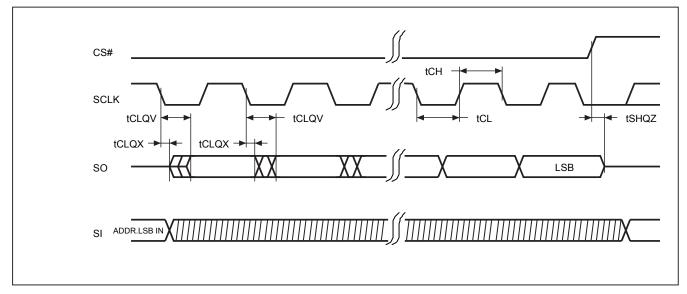




Figure 49. Hold Timing

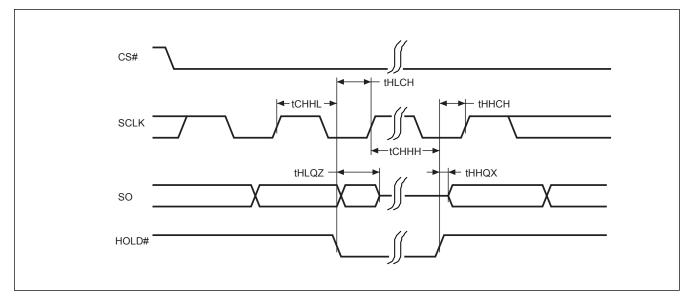


Figure 50. WP# Setup Timing and Hold Timing during WRSR when SRWD=1

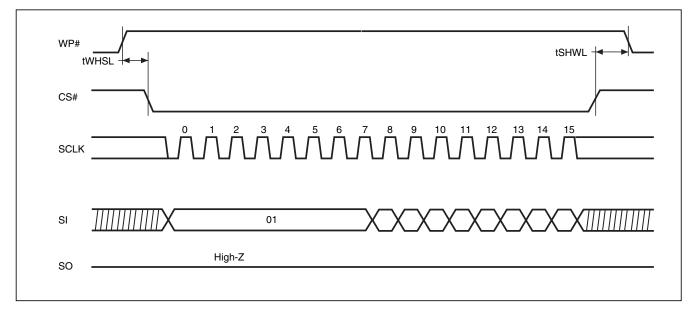
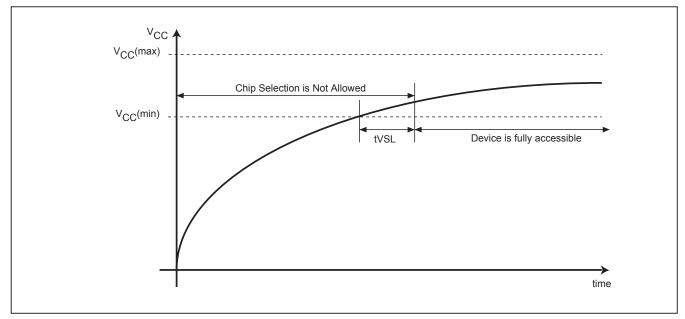




Figure 51. Power-Up Timing



Note: VCC (max.) is 3.6V and VCC (min.) is 2.7V.

13-1. Power-Up Timing

Symbol	Parameter	Min.	Max.	Unit
tVSL(1)	VCC(min) to CS# low	300		us

Note: The parameter is characterized only.

14. INITIAL DELIVERY STATE

The device is delivered with the memory array erased: all bits are set to 1 (each byte contains FFh). The Status Register contains 00h (all Status Register bits are 0).

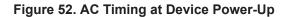


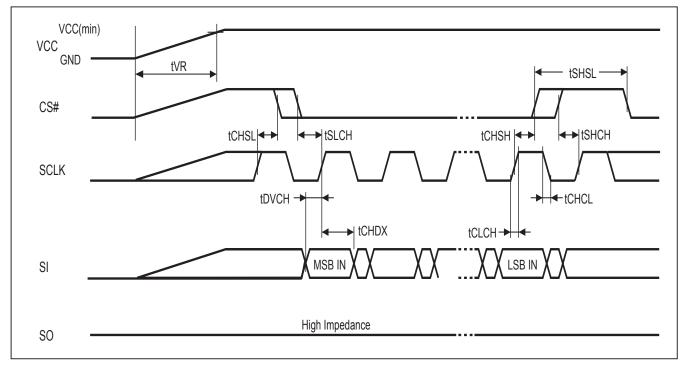
15. OPERATING CONDITIONS

At Device Power-Up and Power-Down

AC timing illustrated in "Figure 52. AC Timing at Device Power-Up" and "Figure 53. Power-Down Sequence" are for the supply voltages and the control signals at device power-up and power-down. If the timing in the figures is ignored, the device will not operate correctly.

During power-up and power-down, CS# needs to follow the voltage applied on VCC to keep the device not to be selected. The CS# can be driven low when VCC reach Vcc(min.) and wait a period of tVSL.





Symbol	Parameter	Notes	Min.	Max.	Unit
tVR	VCC Rise Time	1	20	500000	us/V

Notes :

1. Sampled, not 100% tested.

2. For AC spec tCHSL, tSLCH, tDVCH, tCHDX, tSHSL, tCHSH, tSHCH, tCHCL, tCLCH in the figure, please refer to "12-4. AC CHARACTERISTICS".



Figure 53. Power-Down Sequence

During power-down, CS# needs to follow the voltage drop on VCC to avoid mis-operation.

VCC	
 CS#	
SCLK	



16. ERASE AND PROGRAMMING PERFORMANCE

Parameter	Тур. (1)	Max. (2)	Unit
Write Status Register Cycle Time		40	ms
Sector Erase Time (4KB)	60	300	ms
Block Erase Time (64KB)	0.7	2	S
Block Erase Time (32KB)	0.5	2	S
Chip Erase Time	25	50	S
Byte Program Time (via page program command)	12	300	us
Page Program Time	1.4	5	ms
Erase/Program Cycle	100,000		cycles

Notes:

- 1. Typical program and erase time assumes the following conditions: 25°C, 3.3V, and checker board pattern.
- 2. Under worst conditions of 85°C and 2.7V.
- 3. System-level overhead is the time required to execute the first-bus-cycle sequence for the programming command.

17. DATA RETENTION

Parameter	Condition	Min.	Max.	Unit
Data retention	55°C	20		years

18. LATCH-UP CHARACTERISTICS

	Min.	Max.					
Input Voltage with respect to GND on all power pins, SI, CS#	-1.0V	2 VCCmax					
Input Voltage with respect to GND on SO	-1.0V	VCC + 1.0V					
Current	-100mA	+100mA					
Includes all pins except VCC. Test conditions: VCC = 3.0V, one pin at a time.							

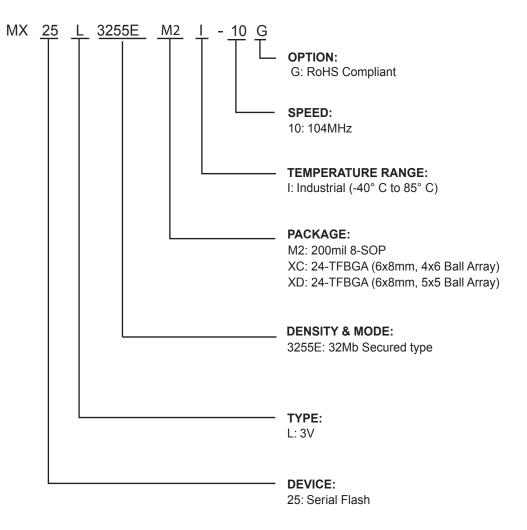


19. ORDERING INFORMATION

PART NO.	CLOCK (MHz)	TEMPERATURE	PACKAGE	Remark
MX25L3255EM2I-10G	104	-40°C~85°C	8-SOP (200mil)	
MX25L3255EXCI-10G	104	-40°C~85°C	24-TFBGA (6X8mm)	4x6 Ball Array
MX25L3255EXDI-10G	104	-40°C~85°C	24-TFBGA (6X8mm)	5x5 Ball Array



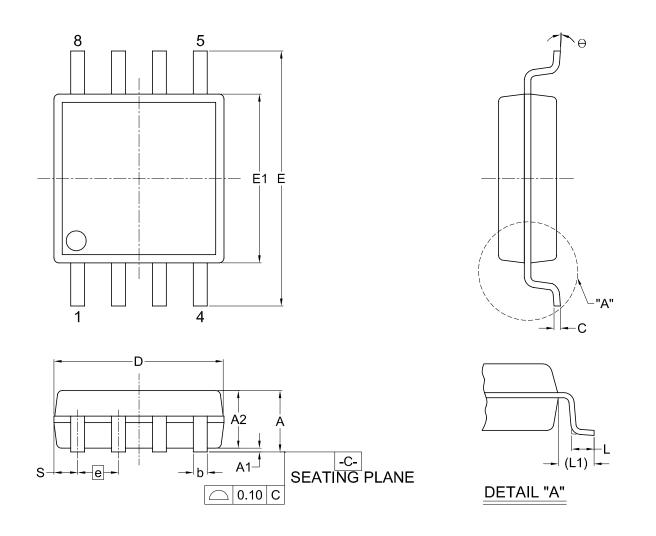
20. PART NAME DESCRIPTION





21. PACKAGE INFORMATION

Doc. Title: Package Outline for SOP 8L 200MIL (official name - 209MIL)



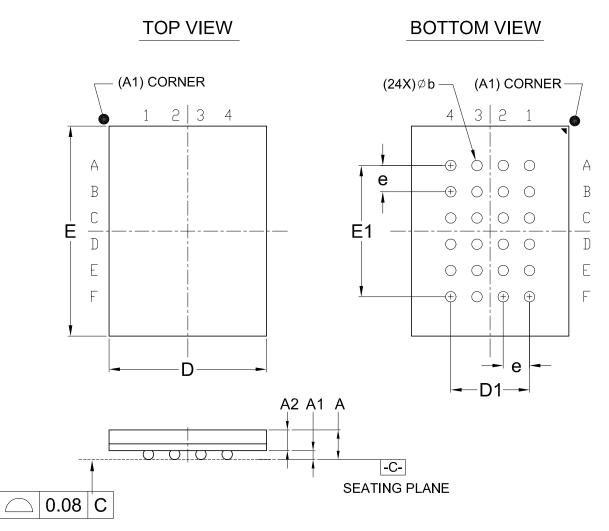
Dimensions (inch dimensions are derived from the original mm dimensions)

SY UNIT		Α	A1	A2	b	с	D	Е	E1	е	L	L1	S	θ
	Min.	-	0.05	1.70	0.36	0.19	5.13	7.70	5.18		0.50	1.21	0.62	0
mm	Nom.		0.15	1.80	0.41	0.20	5.23	7.90	5.28	1.27	0.65	1.31	0.74	5
	Max.	2.16	0.20	1.91	0.51	0.25	5.33	8.10	5.38		0.80	1.41	0.88	8
	Min.		0.002	0.067	0.014	0.007	0.202	0.303	0.204	I	0.020	0.048	0.024	0
Inch	Nom.		0.006	0.071	0.016	0.008	0.206	0.311	0.208	0.050	0.026	0.052	0.029	5
	Max.	0.085	0.008	0.075	0.020	0.010	0.210	0.319	0.212	ļ	0.031	0.056	0.035	8

Dwg. No.	Revision		Refe	erence	
	Kevision	JEDEC	EIAJ		
6110-1406	3				



Doc. Title: Package Outline for CSP 24BALL (6x8x1.2MM, BALL PITCH 1.0MM, BALL DIAMETER 0.4MM)



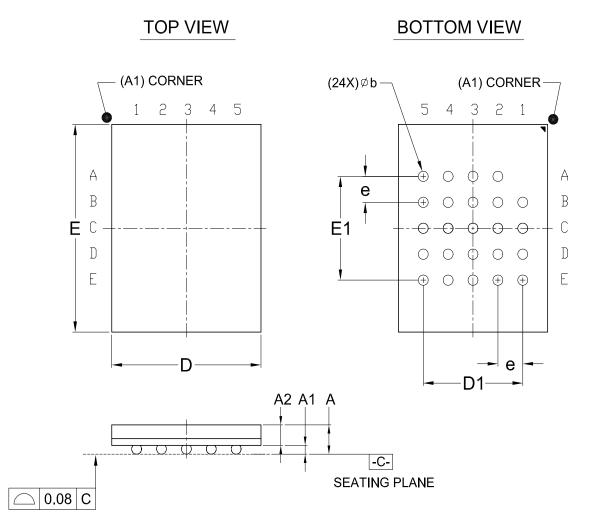
Dimensions (inch dimensions are derived from the original mm dimensions)

SY UNIT		A	A1	A2	b	D	D1	E	E1	е
	Min.	-	0.25	0.65	0.35	5.90		7.90		
mm	Nom.	-	0.30		0.40	6.00	3.00	8.00	5.00	1.00
	Max.	1.20	0.35		0.45	6.10		8.10		
	Min.		0.010	0.026	0.014	0.232		0.311		
Inch	Nom.		0.012		0.016	0.236	0.120	0.315	0.200	0.039
	Max.	0.047	0.014		0.018	0.240		0.319		

Dwg. No.	Revision	Reference				
		JEDEC	EIAJ			
6110-4257	2	MO-216				



Doc. Title: Package Outline for CSP 24BALL (6x8x1.2MM, BALL PITCH 1.0MM, BALL DIAMETER 0.4MM, 5x5 BALL ARRAY)



Dimensions (inch dimensions are derived from the original mm dimensions)

SY UNIT	(MBOL	Α	A1	A2	b	D	D1	E	E1	е
	Min.		0.25	0.65	0.35	5.90		7.90		
mm	Nom.		0.30		0.40	6.00	4.00	8.00	4.00	1.00
	Max.	1.20	0.35		0.45	6.10		8.10		
Inch	Min.		0.010	0.026	0.014	0.232		0.311		
	Nom.		0.012		0.016	0.236	0.157	0.315	0.157	0.039
	Max.	0.047	0.014		0.018	0.240		0.319		

Dwg. No.	Revision	Reference				
		JEDEC	EIAJ			
6110-4257.1	1					



MX25L3255E

22. REVISION HISTORY

Revisior	No. Description	Page	Date
0.01	1. Modified Low standby current to 80uA (max).	P4/72	JUL/23/2012
	2. Modified Deep power-down current to 40uA (max).	P4/72	



Except for customized products which have been expressly identified in the applicable agreement, Macronix's products are designed, developed, and/or manufactured for ordinary business, industrial, personal, and/or household applications only, and not for use in any applications which may, directly or indirectly, cause death, personal injury, or severe property damages. In the event Macronix products are used in contradicted to their target usage above, the buyer shall take any and all actions to ensure said Macronix's product qualified for its actual use in accordance with the applicable laws and regulations; and Macronix as well as it's suppliers and/or distributors shall be released from any and all liability arisen therefrom.

Copyright© Macronix International Co., Ltd. 2012. All rights reserved, including the trademarks and tradename thereof, such as Macronix, MXIC, MXIC Logo, MX Logo, Integrated Solutions Provider, NBit, Nbit, NBit, Macronix NBit, eLiteFlash, HybridNVM, HybridFlash, XtraROM, Phines, KH Logo, BE-SONOS, KSMC, Kingtech, MXSMIO, Macronix vEE, Macronix MAP, Rich Audio, Rich Book, Rich TV, and FitCAM. The names and brands of third party referred thereto (if any) are for identification purposes only.

MACRONIX INTERNATIONAL CO., LTD. reserves the right to change product and specifications without notice.